



Nanopositioning at Sirius/LNLS beamlines

a review and future opportunities

November 9th, 2023

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MINISTRY OF
SCIENCE, TECHNOLOGY
AND INNOVATION



Outline

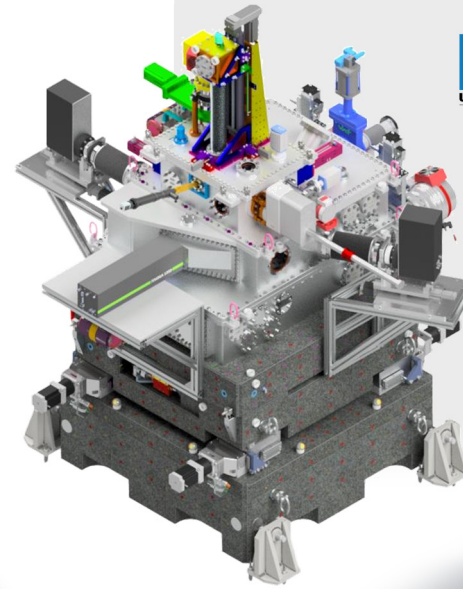
- Introduction
- Motivation
- Commercial Scenario
- Development Framework
- Examples
- Conclusions & Perspectives

Outline

- Introduction
 - 1. Short Biography
 - 2. The CNPEM, the LNLS and Sirius
- Motivation
- Commercial Scenario
- Development Framework
- Examples
- Conclusions & Perspectives

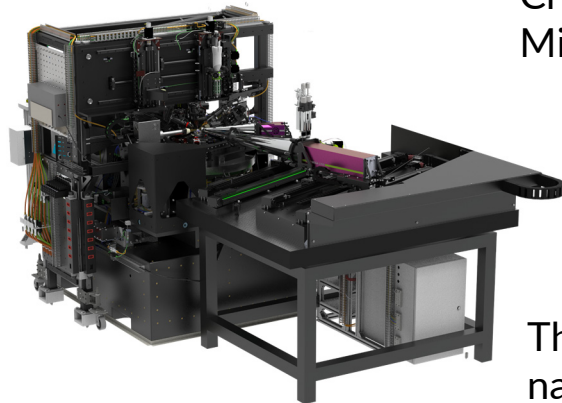
1. Short Biography

- Bachelor in Engineering Physics (UFSCar, Brazil)
- Master in Physics w/ emphasis in Scientific Instrumentation (CBPF, Brazil)
- PhD in Mechatronics (TU/e, The Netherlands)
- 14 years at the LNLS (UVX and Sirius)
 - Head of the Precision Engineering and Mechatronics group (MEP)

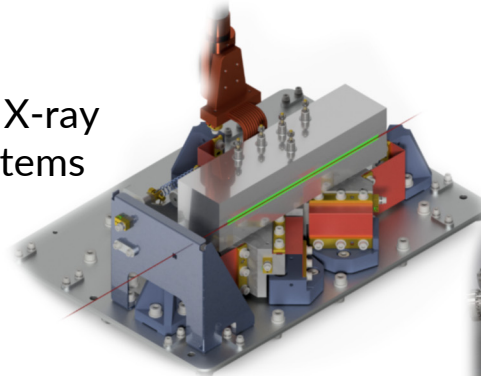


The SAPOTI nanoprobe

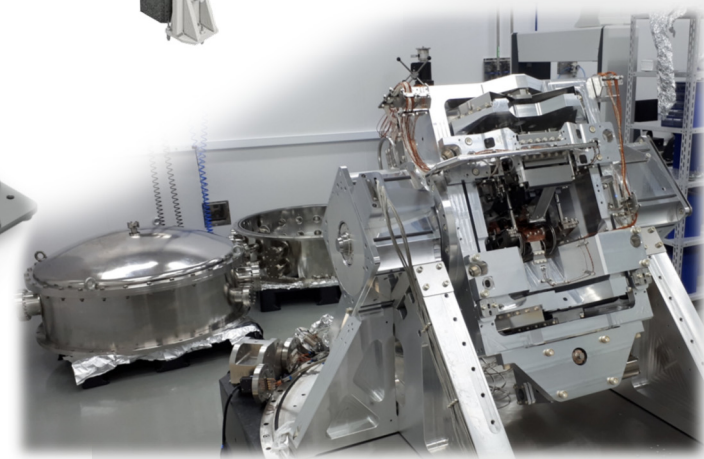
The HD-DCM



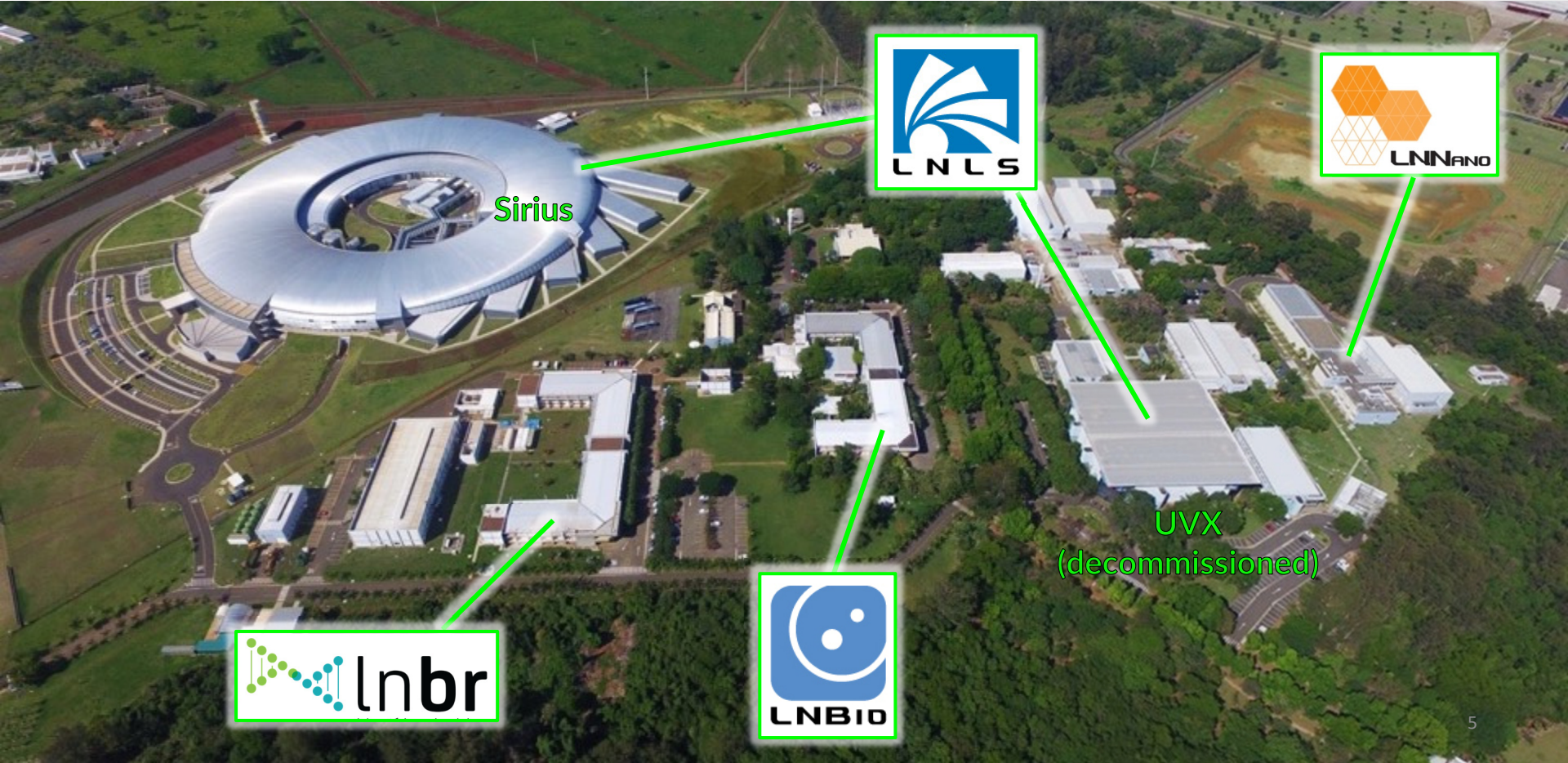
Cryogenic X-ray Mirror Systems



The TARUMÃ nanoprobe



2. The CNPEM and the LNLS



2. 4th Generation Storage Rings Worldwide



CNPEM

APS-U

Energy 6.0 GeV
Circumference 1103 m
Natural emittance 42 pm.rad
Current (top-up) 200 mA

MAX IV

Energy 3.0 GeV
Circumference 528 m
Natural emittance 330 pm.rad
Current (top-up) 500 mA

SIRIUS

Energy 3.0 GeV
Circumference 518 m
Natural emittance 250 pm.rad
Current (top-up) 350 mA



2024/2025

HEPS

Energy 6.0 GeV
Circumference 1360 m
Natural emittance < 60 pm.rad
Current (top-up) 200 mA



ESRF-EBS

Energy 6.0 GeV
Circumference 844 m
Natural emittance 133 pm.rad
Current (top-up) 200 mA



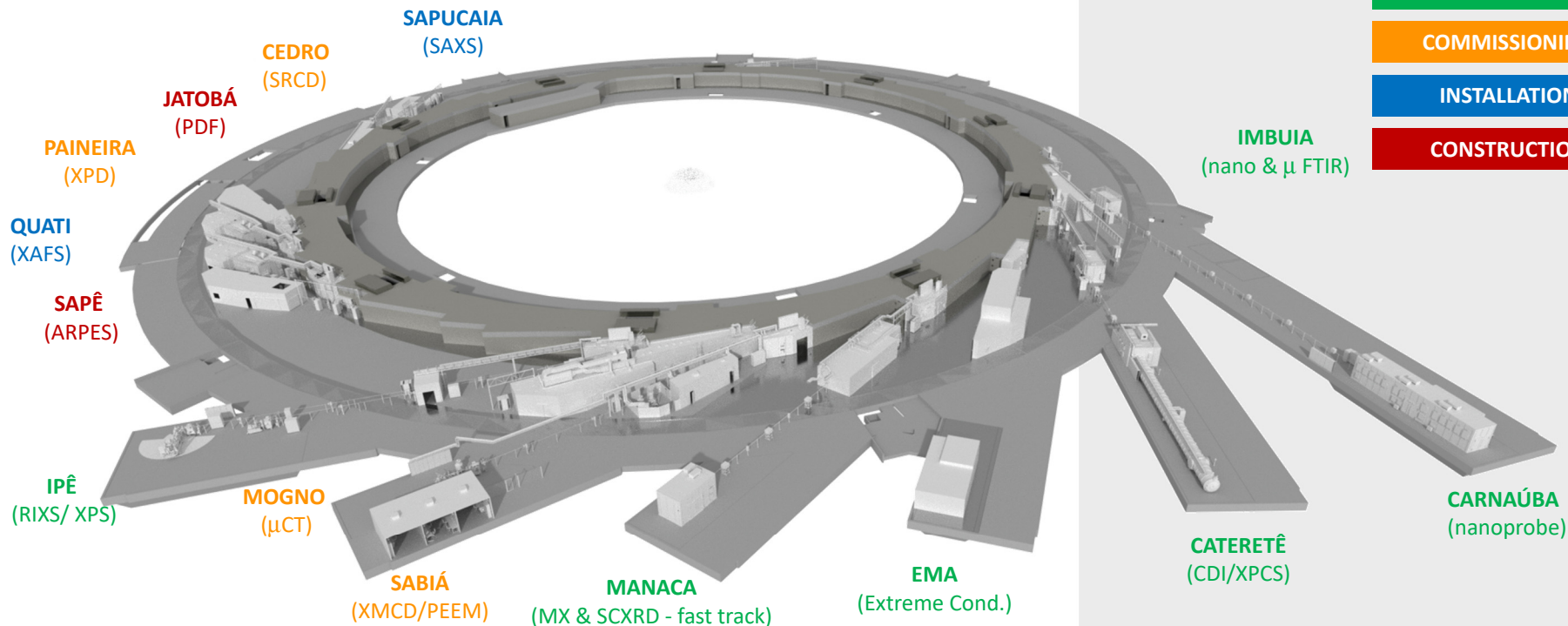
Campinas

Sirius Project goals

- Optimized for **coherence** in tender X-rays
- High-brilliance **hard X-rays** for Spectroscopy and Imaging
- Maintaining the **IR and UV** science programs

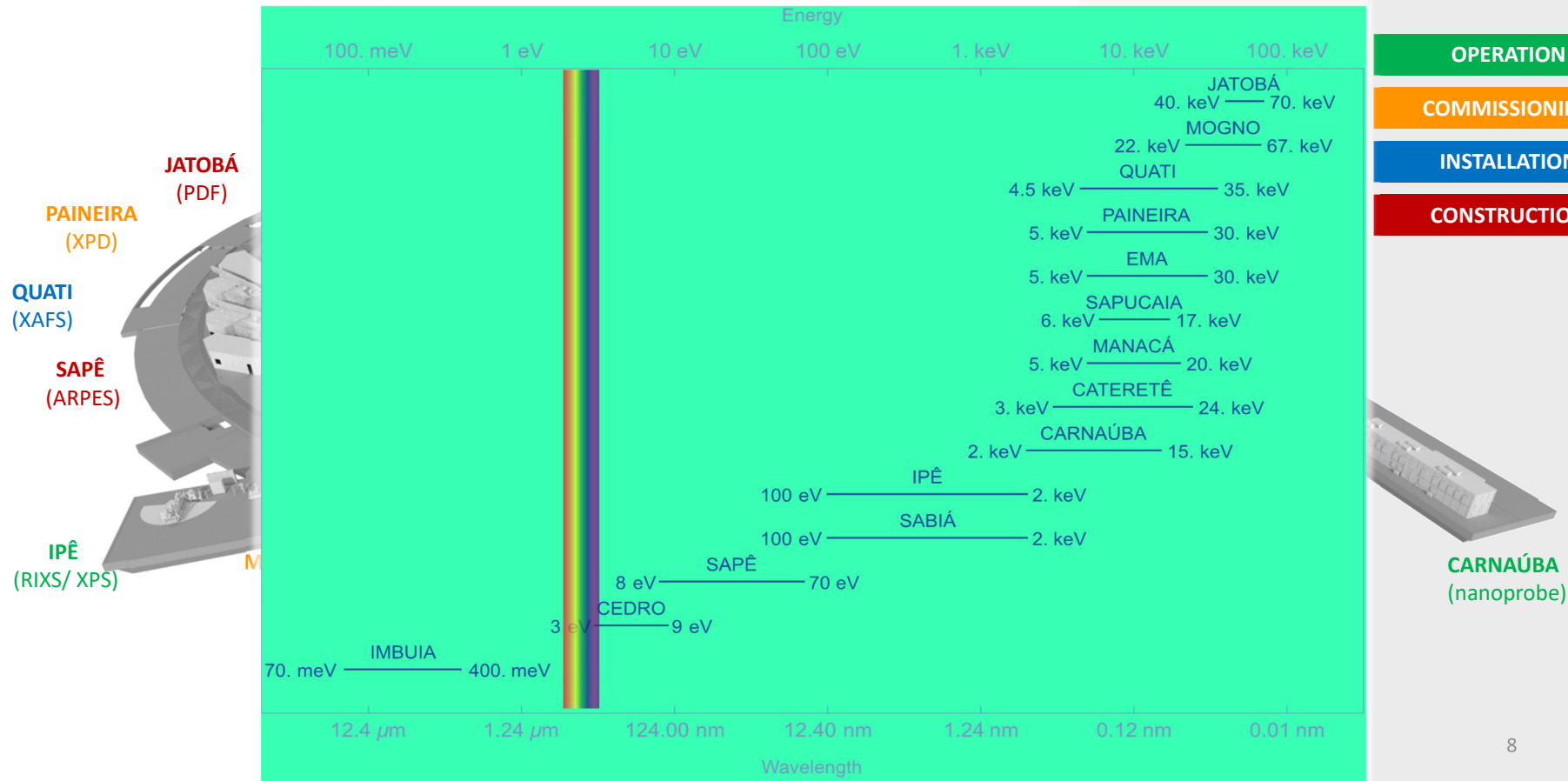
2. Sirius Beamlines – Phase 1

<https://www.lnls.cnpem.br/beamlines/>



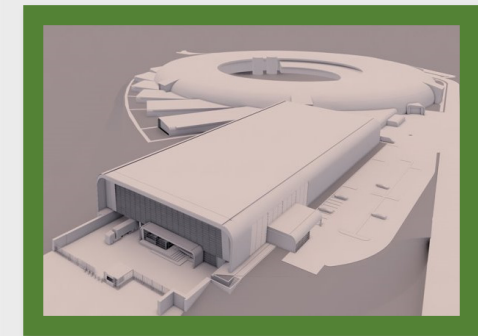
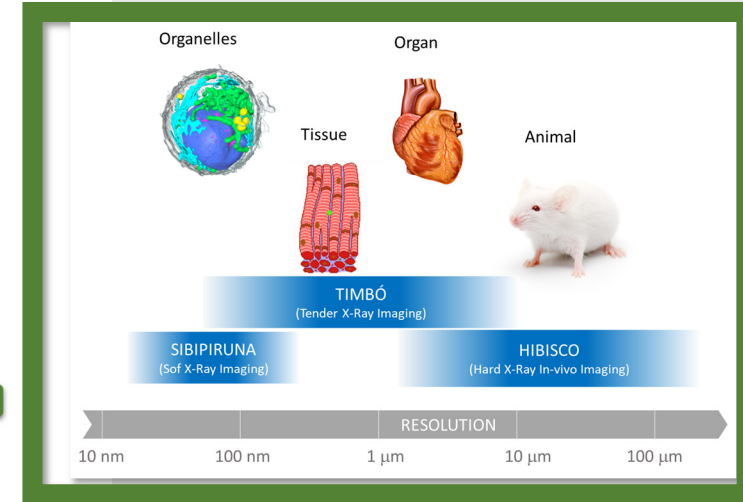
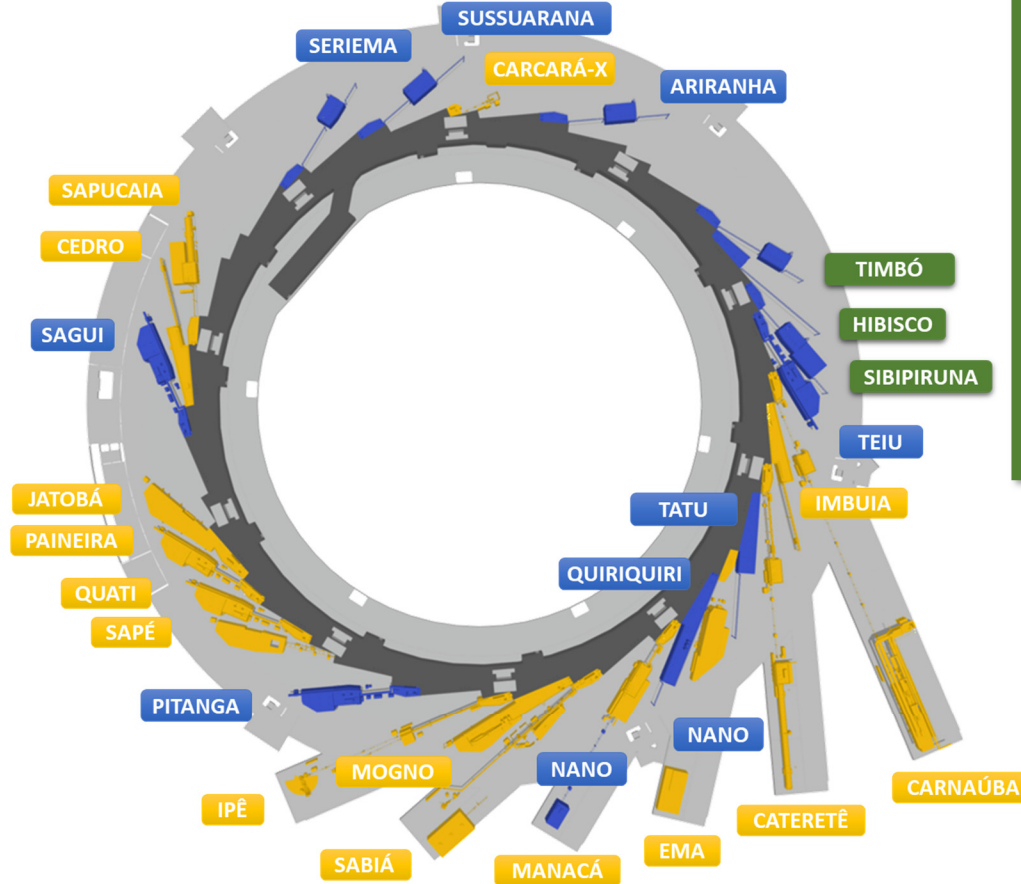
2. Sirius Beamlines – Phase 1

<https://www.lnls.cnpem.br/beamlines/>



2. Sirius Beamlines – Phase 2 and Orion

- PHASE I
- PHASE II
- ORION

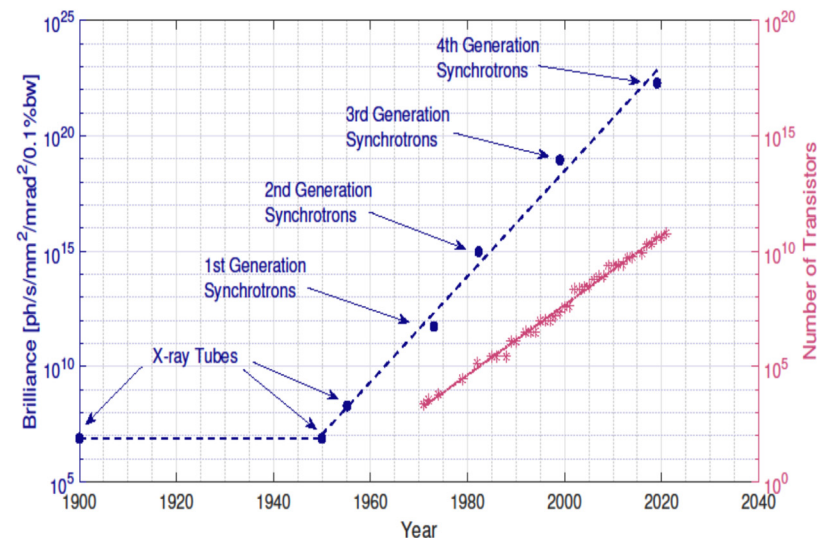


Outline: Nanopositioning

- Introduction
- Motivation: **Why** do we need it?
- Commercial Scenario
 - 1. New light sources
 - 2. Beam delivery
 - 3. Experimental Methods
- Development Framework
- Examples
- Conclusions & Perspectives

1. New-generation light sources

- Increased brilliance/flux
 - **Smaller sources** → Higher stability
 - **Higher flux** → Faster processes
- Increased **coherence** fractions
 - Coherence-based methods (ptycho)
 - Higher stability requirements



UVX

Max. Intensity = 1.7e+09 ph/s/0.1%/mm²

Window: 6.0 x 0.4 mm²

Sirius

Max. Intensity = 6.6e+16 ph/s/0.1%/mm²

Window: 6.0 x 0.4 mm²

2nd Generation UVX to 4th Generation Sirius at the LNLS

2. Beam Delivery

2.1. Mirrors

2.2. Double-Crystal Monochromators

2.3. Plane-Grating Monochromators

2.4. KB Mirrors

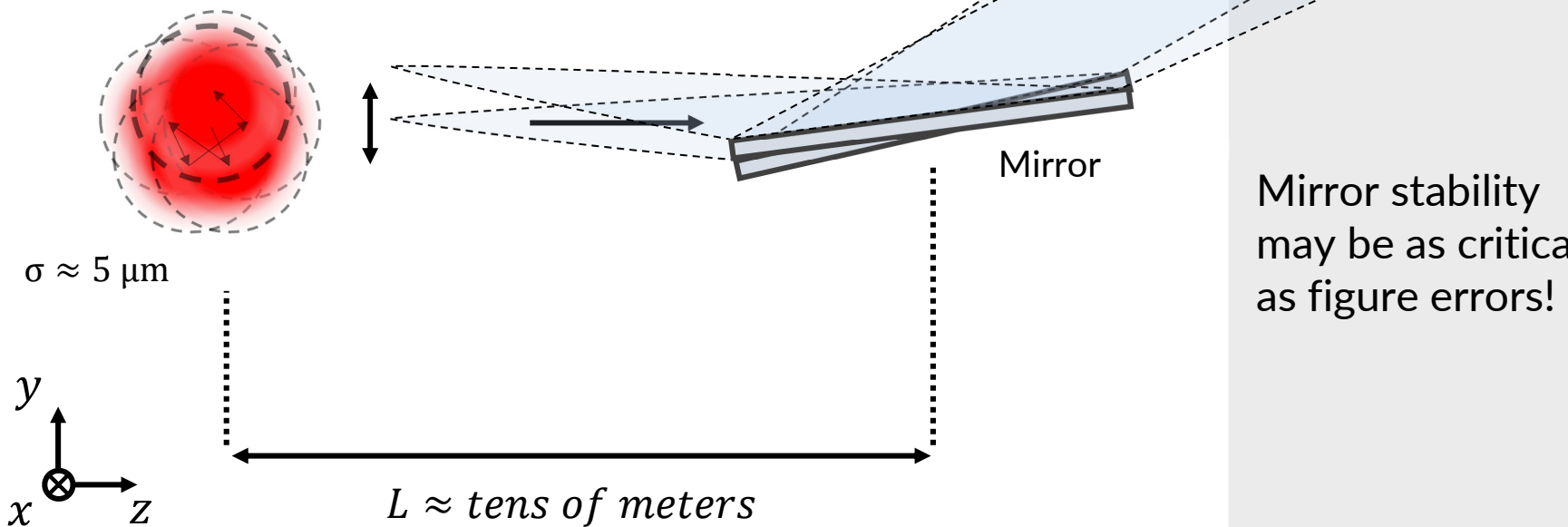
2.1. Mirrors

Disturbed source
(xy-plane)

For stability levels of 10% of σ :

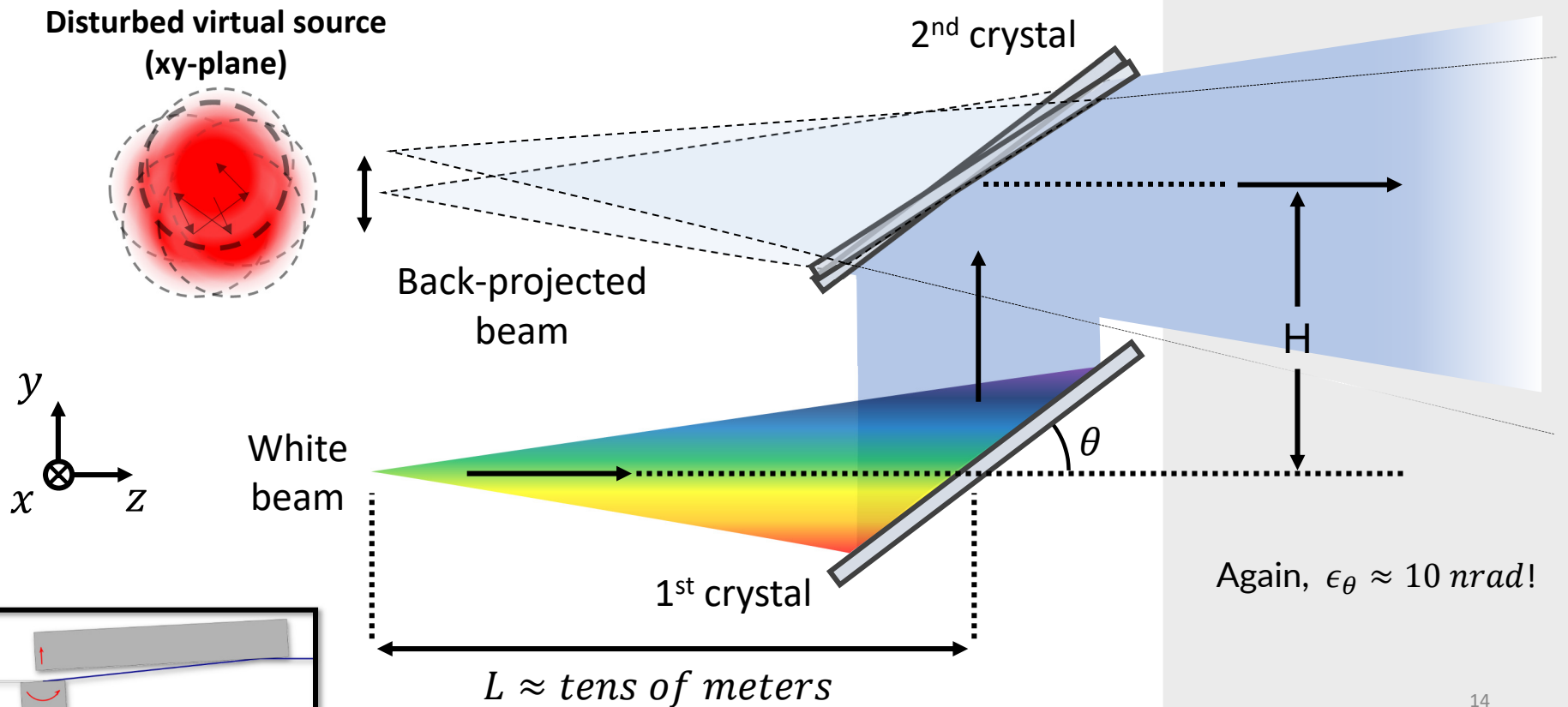
$$\epsilon_{\theta} \approx \frac{0.5 \mu\text{m}}{50 \text{ m}} \approx 10 \text{ nrad}$$

(10 nrad = 1 nm / 100 mm)



Mirror stability
may be as critical
as figure errors!

2.2. Double-Crystal Monochromators



2.3. Plane-Grating Monochromators

Veritas @ Max IV

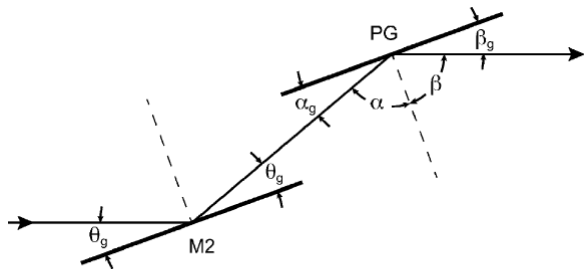


Figure 1
Schematic picture of the geometry of the collimated plane grating monochromator. M2 denotes the mirror and PG the plane grating. The light comes in from the left and exits towards the slit to the right. The incoming and outgoing beams are parallel to each other.

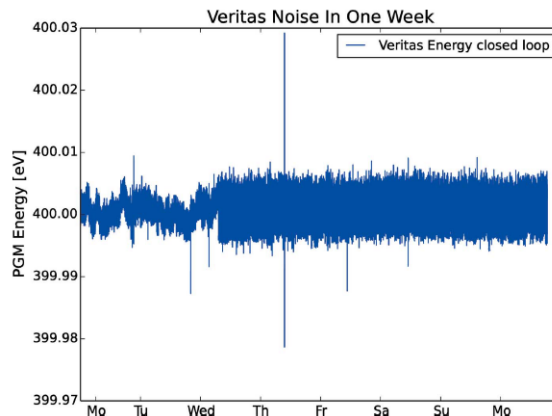


Figure 22
Veritas PGM in closed loop was standing still for one week while the energy was sampled. Mid-week, the cooling water was turned on increasing the noise from 3 meV to 7 meV.

(doi:10.1107/S1600577520000843)

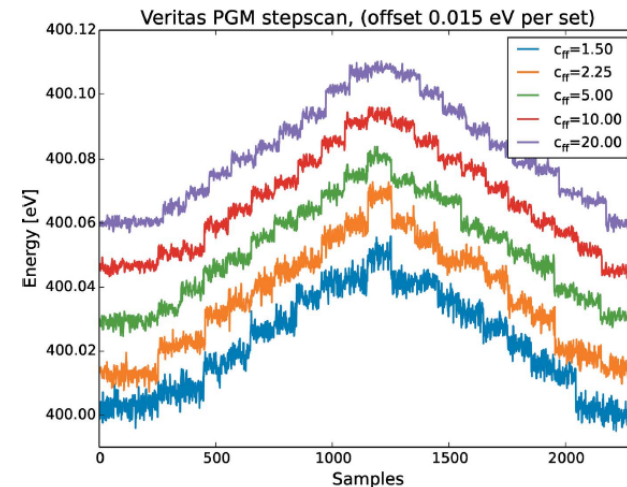
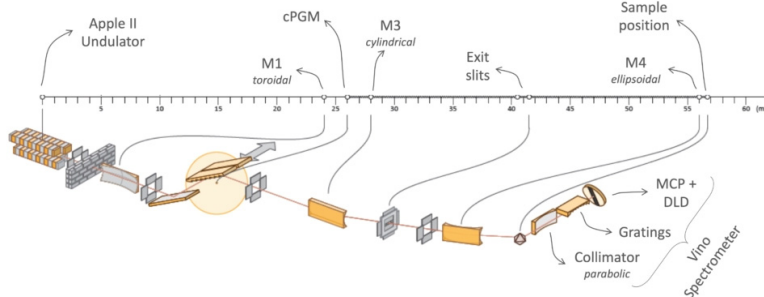


Figure 7
The sampled angular noise in encoder position converted to energy for small energy steps for different c_{ff} values at Veritas. Each step is 5 meV and 10 s at 400 eV giving a resolution of 80000. The system behaviour is better at higher c_{ff} values. The cooling water is turned off.



Angular stability, affecting energy resolution!

2.4. KB (Kirkpatrick-Baez) Systems

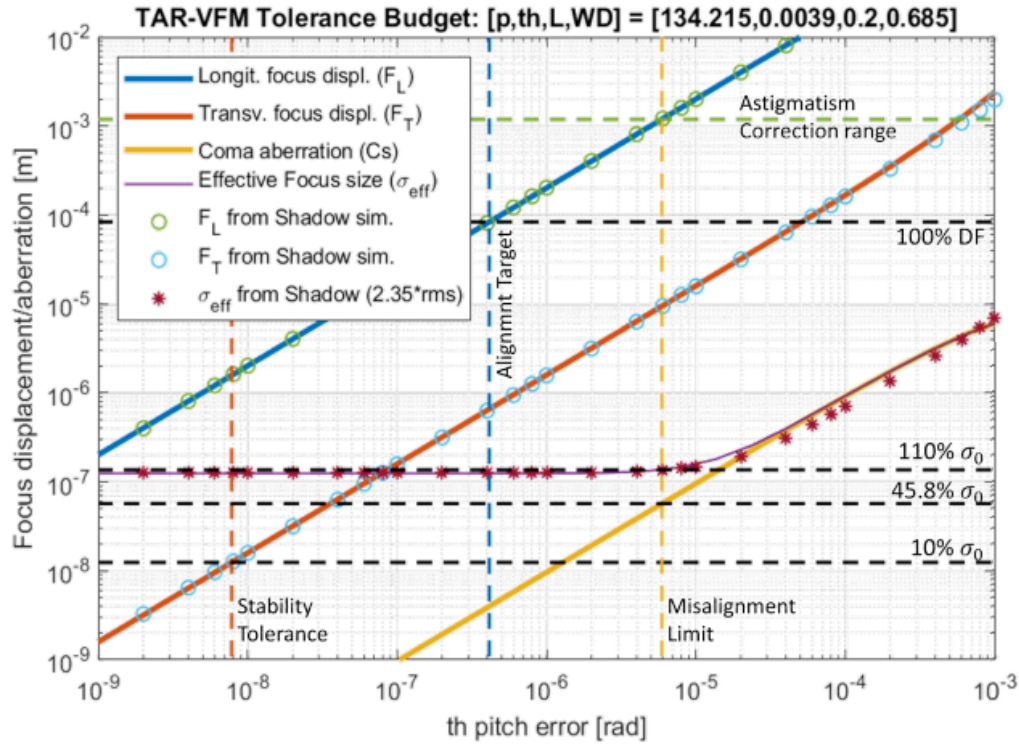
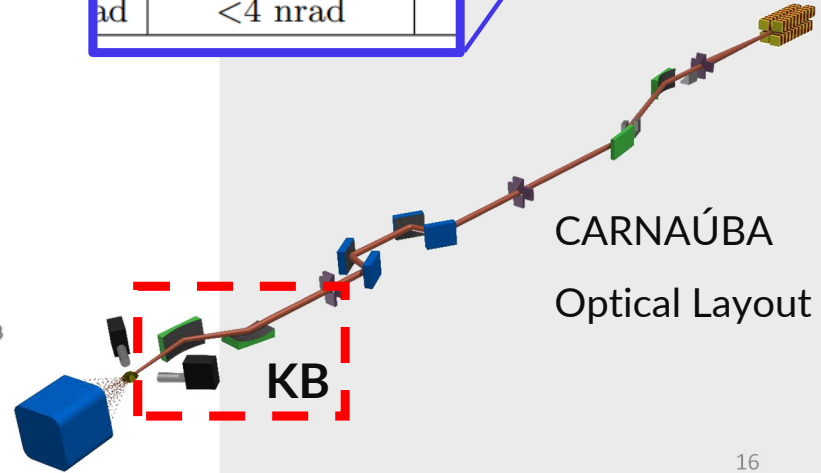


Table 1. KB set specifications for first Sirius Nanoprobes

KB set	Focus size	Depth of Focus	Max.mir. Length	Working distance	Grazing angle	Pitch stab. tolerance	Surface error tol.	#stripes
TARUMÁ	120 nm	80 μ m	210 mm	450 mm	3.9 mrad	<10 nrad	<1 nm	1
MOGNO	100 nm	20 μ m	450 mm	175 mm	3.8 mrad	<8 nrad	<1 nm	2
SAPOTI	35 nm	5 μ m	300 mm	55 mm	3.9 mrad	<4 nrad	<1 nm	1

Sirius Nanoprobes

Angle	Pitch stab. tolerance	Surf. error tol.
ad	<10 nrad	
ad	<8 nrad	
ad	<4 nrad	



(doi: 10.1088/1742-6596/2380/1/012074)

[Credit: Gabriel Moreno]

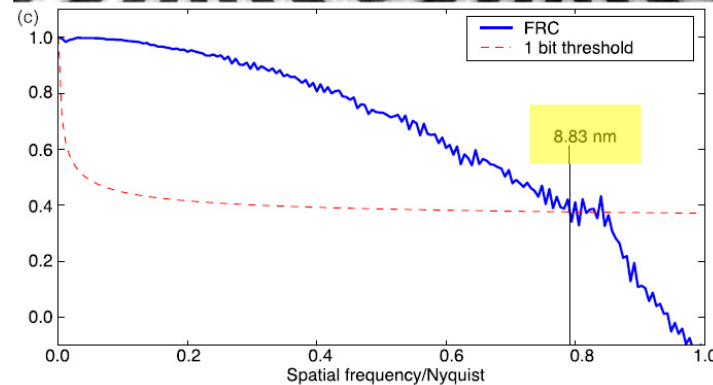
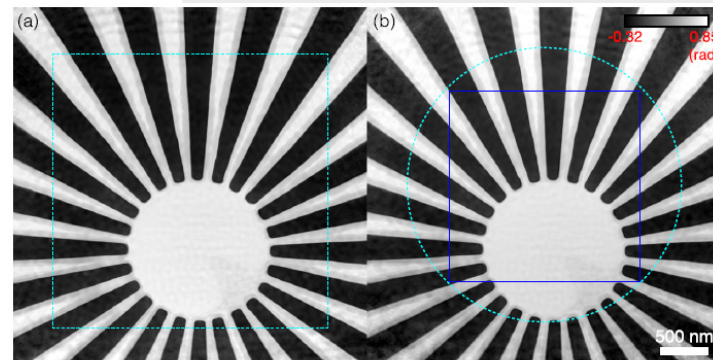
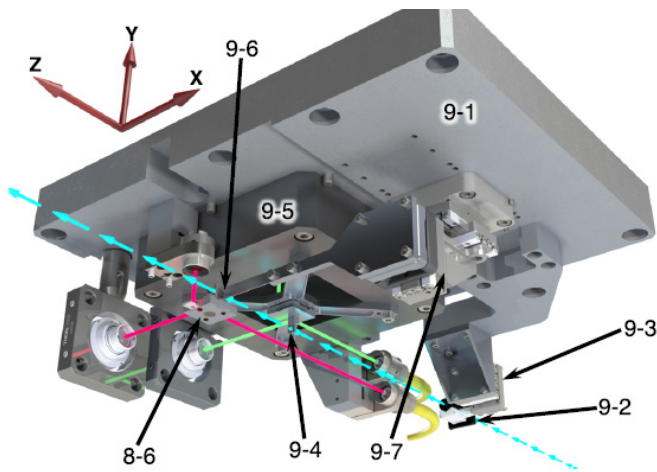
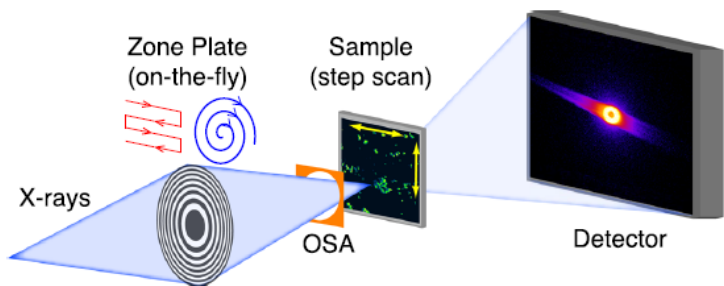
3. Experimental Methods

Scanning Microscopes

- 2D images (STXM, Ptychography, Fluorescence)
- 3D Tomography

3. Experimental Methods: Ptycho-Tomography

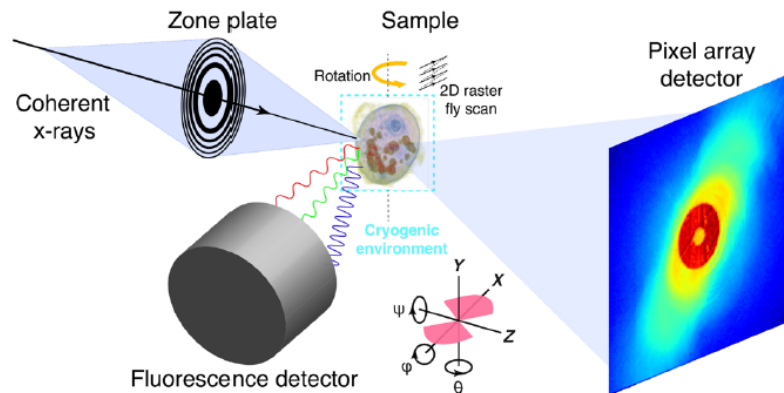
Velociprobe @ APS



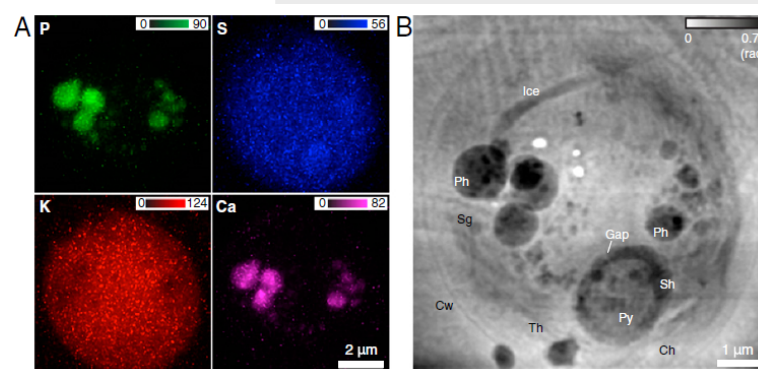
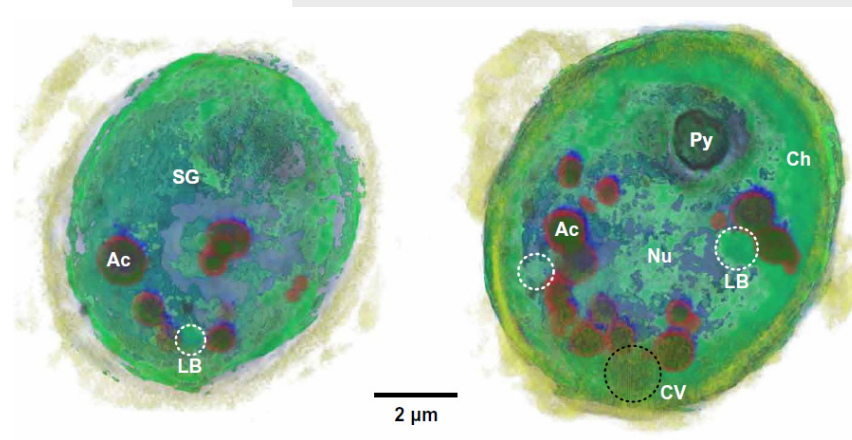
(doi: 10.1063/1.5103173)

3. Experimental Methods: Ptycho-Fluoro-Tomography

Bionanoprobe @ APS



(doi: 10.1126/sciadv.aau4548)



(doi: 10.1073/pnas.1413003112)

Outline: Nanopositioning

- Introduction
- Motivation
- Commercial Scenario: **What** is out there?
- Development Framework
 - 1. Commercial Systems
 - 2. Standards and Procedures
- Examples
- Conclusions & Perspectives

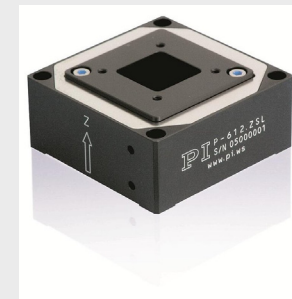
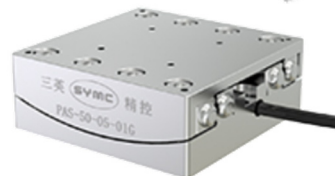
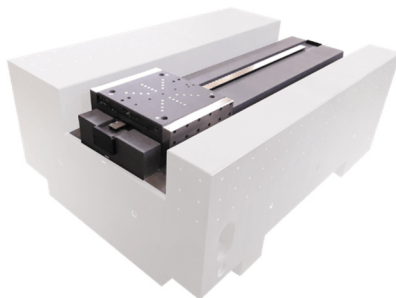
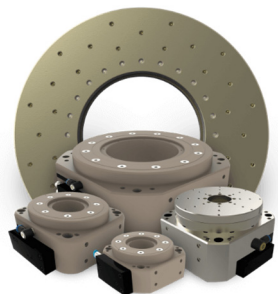
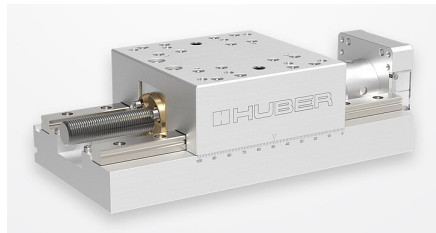
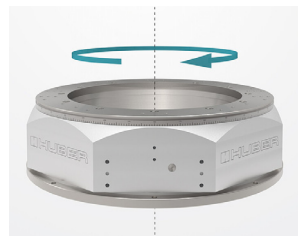
1. Commercial Systems

1.1. Positioning Systems

1.2. Complete Instruments

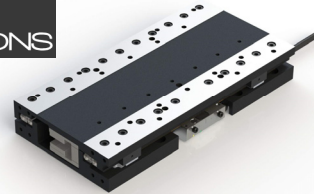
1.1. Positioning Systems

and many others...



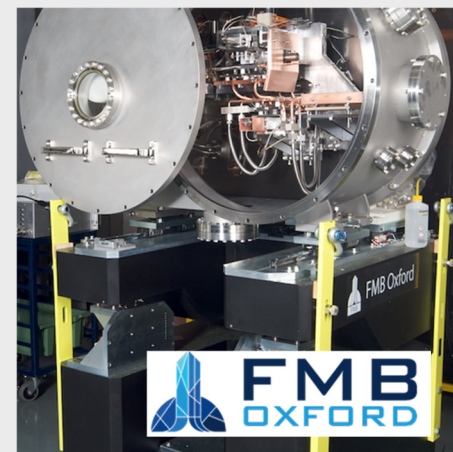
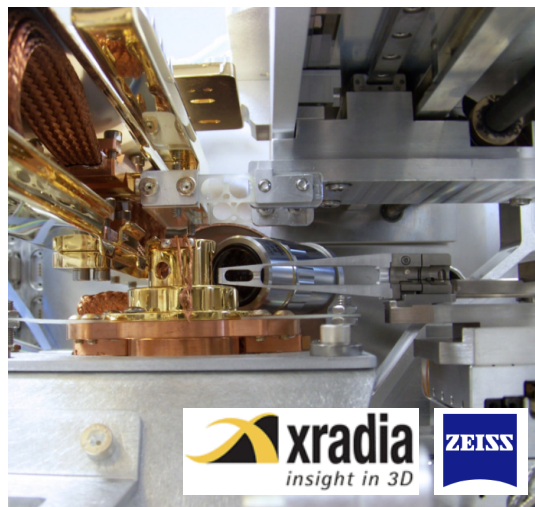
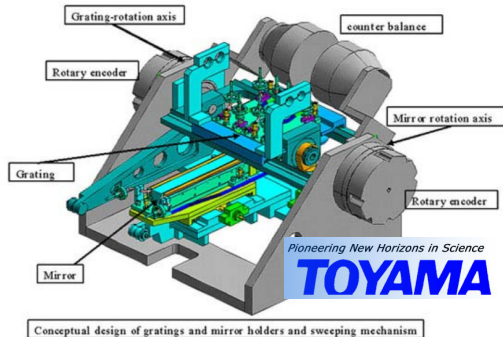
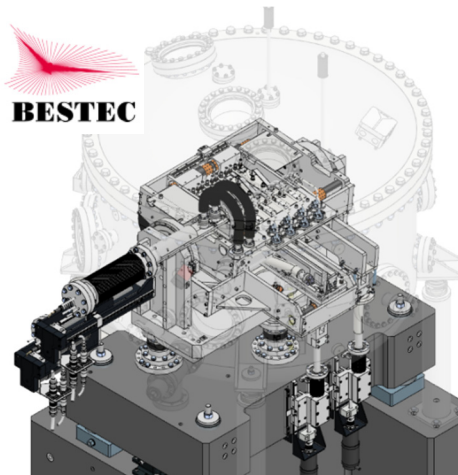
1.1. Positioning Systems

and many others...



1.2. Complete Instruments

and many others...



2. Standards and Procedures

2.1. Linear Positioning Systems: ASME B5.64

2.2. Rotary Systems: Spindle Metrology

*Comparing complete instruments being very challenging.

2.1. Linear Positioning Systems: ASME B5.64



CNPEM

ASME B5.64

- Characterization Guide
- Performance Tests
- Unified Terminology
- Statistics and Correction Methods



Greg Vogl is an Engineer in Production Systems Group @ NIST



Steve Ludwick is Director of Sustaining Engineering @ Aerotech

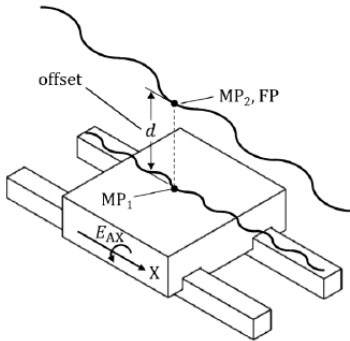


Jimmie Miller is Chief Engineer of Center for Precision Metrology @ UNCC

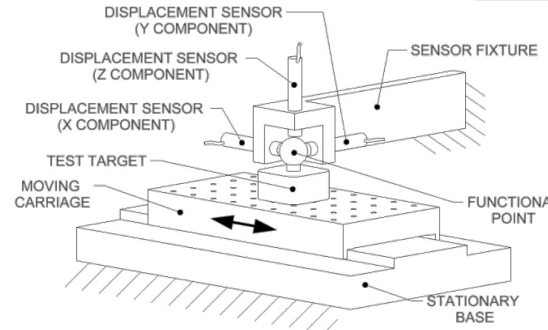
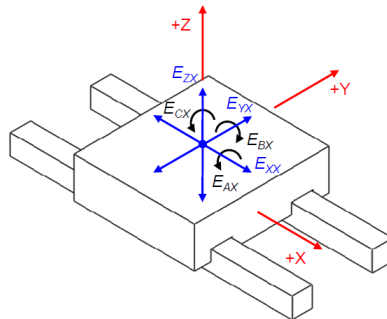


Axel Grabowski is Head of R&D of Sensor Technologies Department @ Physik Instrumente (PI)

ASPE 2022

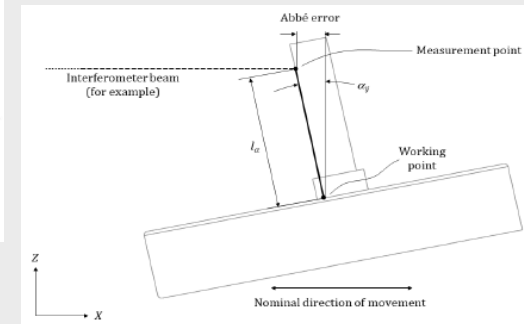


Positioning Error Motion Nomenclature



Point Repeatability

Metrology Corrections



Measurement Point (MP)
vs
Functional Point (FP)

2.1. Linear Positioning Systems: ASME B5.64

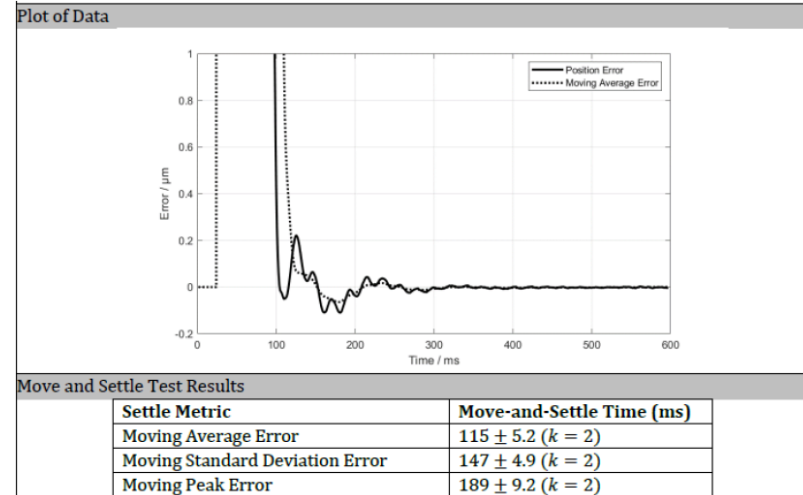
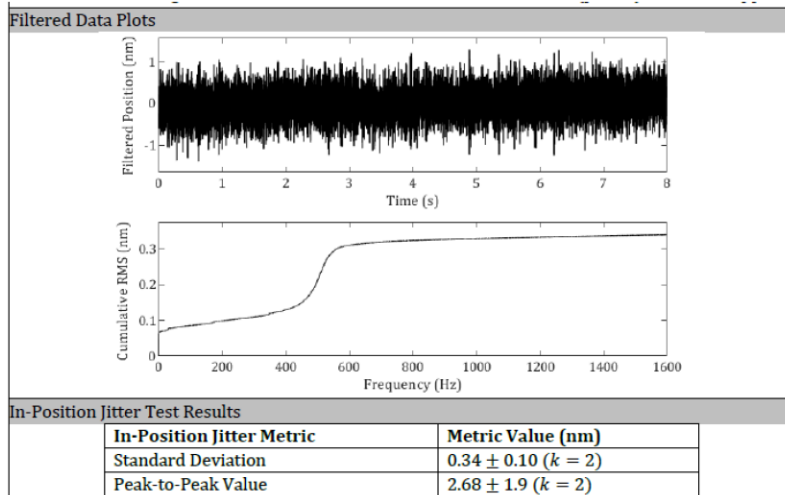


In-Position “Jitter”

- Setup/assembly
- Sensor type
- Acquisition (period, filters, etc.)
- Uncertainty Analysis
- Data presentation

Move and Settle

- In-position remarks +
- *Travel distance*
- *Settling Criteria*



2.1. Linear Positioning Systems: ASME B5.64

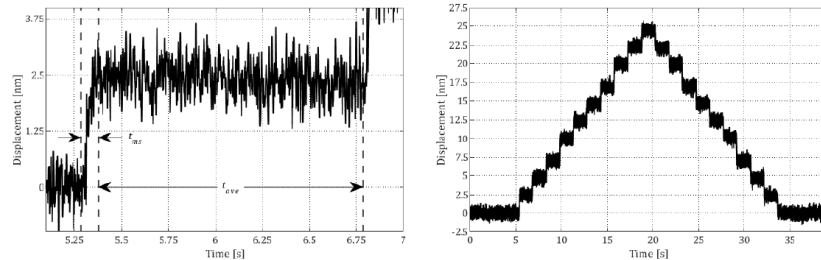
Incremental and Minimum Step Motion Test

- In-position remarks +
- *Step size*
- *Uni/bidirectional*
- *Number of steps*
- *Step reversal error*
- *Minimum incremental motion*

Corrections

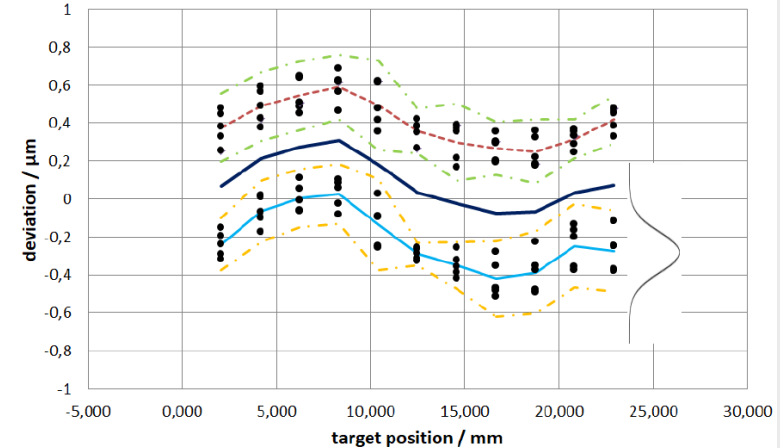
- Thermal drift
- Abbé errors (angle meas. and compensation)
- Uni/bidirectional deviation
- System reversal error
- Linearity correction methods

Plots of Filtered Data

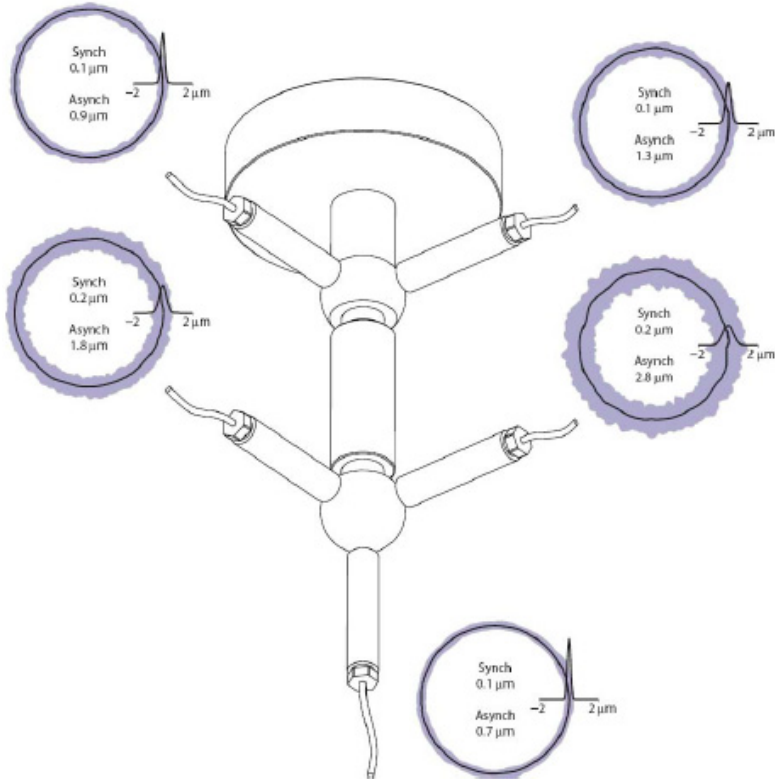


Incremental Step Test Results

	Direction of Motion		
	Forward	Reverse	Combined
Sample Mean, \bar{X}_{inc} (nm)	2.51	2.53	2.52
Sample Standard Deviation, s_{inc} (nm)	0.051	0.074	0.065

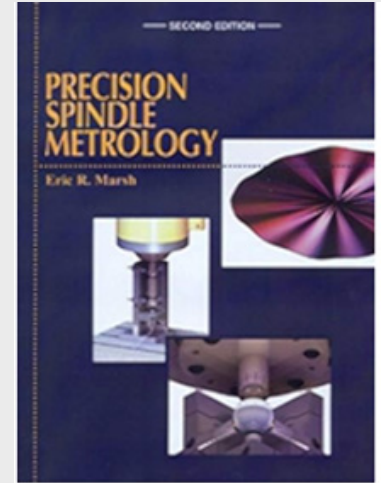


2.2. Rotary Systems: Spindle Metrology



Precision Spindle Metrology (by Erik Marsh)

- Metrology concepts
- Test Instrumentation
- Data acquisition
- Data analysis



Erik Marsh



<https://www.ibspe.com/machine-qualification/spindle-analyzer-systems>

*Tests using capacitive probes

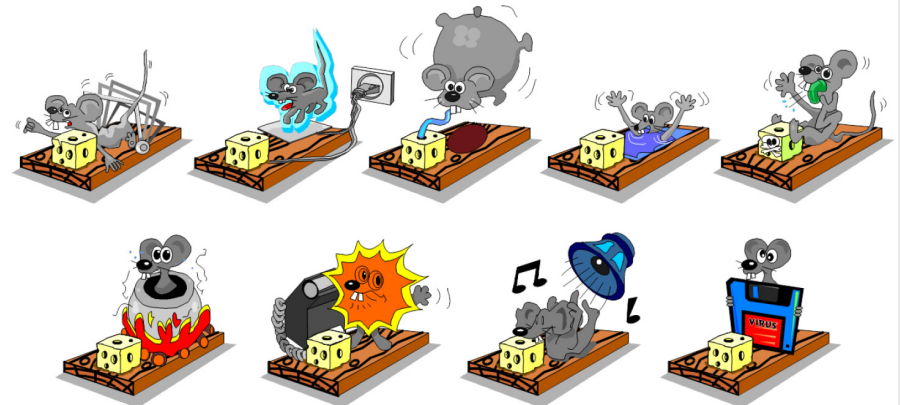
Outline: Nanopositioning

- Introduction
- Motivation
- Commercial Scenario
- Development Framework: **How** can we think about it?
- Examples
 - 1. Systems Engineering (SE)
 - 2. Design Principles
 - 3. Integration
- Conclusions & Perspectives

1. Systems Engineering

- Requirements engineering (Problem Domain vs Solution Domain)
- Modularization (Product Breakdown)
- Functional Breakdown
- Competence Management
- Error Budgeting
- Modeling

[Credit: Prof. Jan van Eijk]



Meant to increase efficiency
and reduce redesign/rework!

<https://hightechsystems.nl/artikel/kijk-buiten-de-grenzen-van-je-eigen-koninkrijkje/>

2. Design Principles

2.1. References

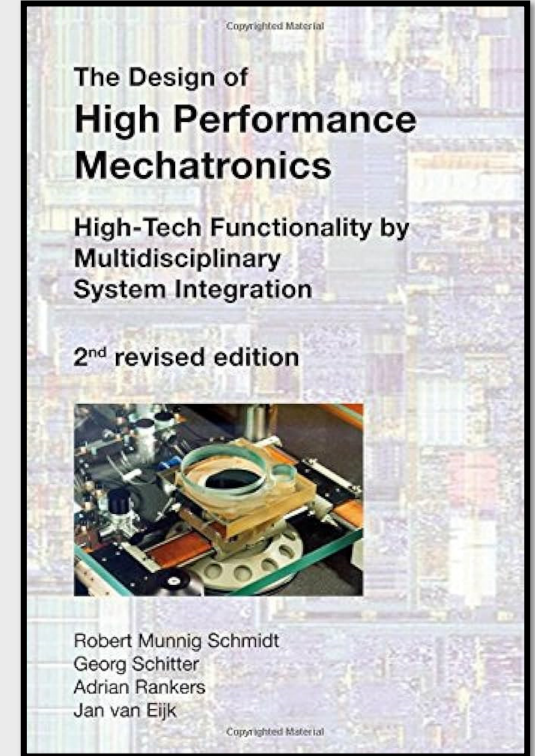
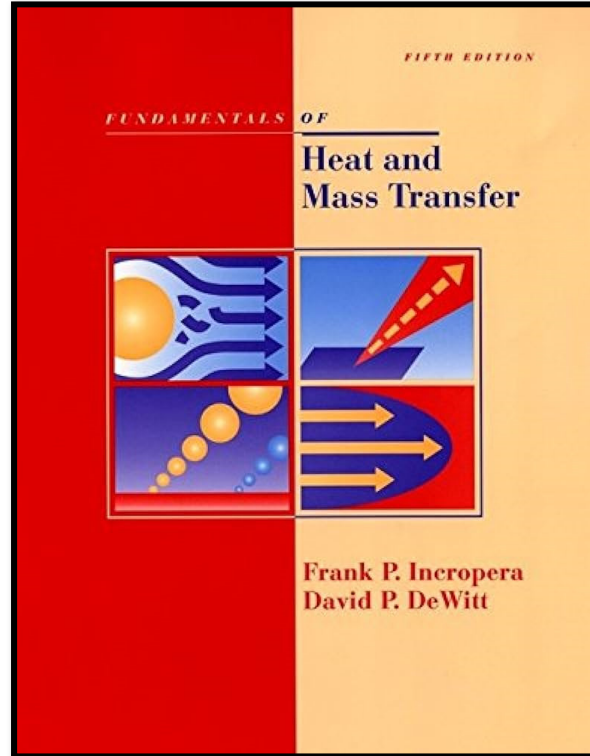
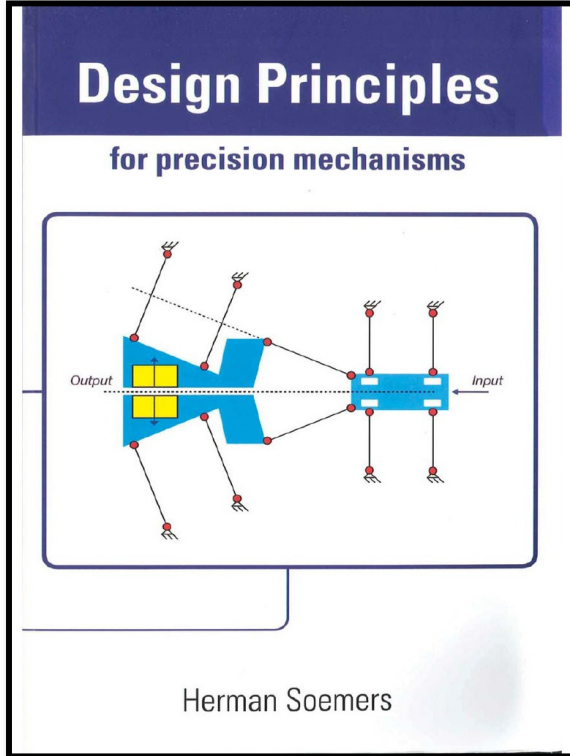
2.2. The 11 Design Principles of High-Precision Machines

2.3. Mechanical

2.4. Dynamics

2.5. Thermal

2.1. References



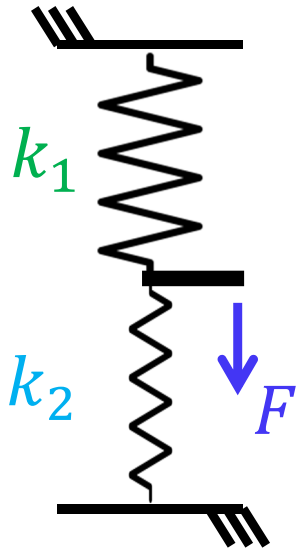
2.2. The 11 Design Principles

Design of High Precision Machines:

1. Structure (symmetry, stiffness, dynamics, damping)
2. Kinematic/Semi-kinematic design (isostatic)
3. Abbé Principle (metrology)
4. Direct measurement
5. Metrology frames (isolated from force frames)
6. Bearings
7. Transmission drives
8. Thermal effects
9. Control
10. Error Budgeting (static, dynamic, thermal)
11. Error Compensation

2.3. Mechanical: Design for Stiffness

Parallel Arrangement



$$k_{eff} = k_1 + k_2$$

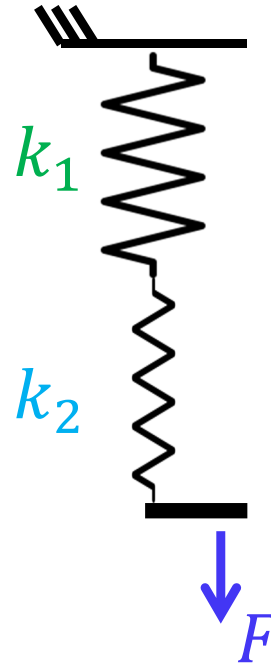


Dominated by the strongest element

$$(k_{eff} > \max(k_1, k_2))$$

$$k_1 > k_2$$

Series Arrangement



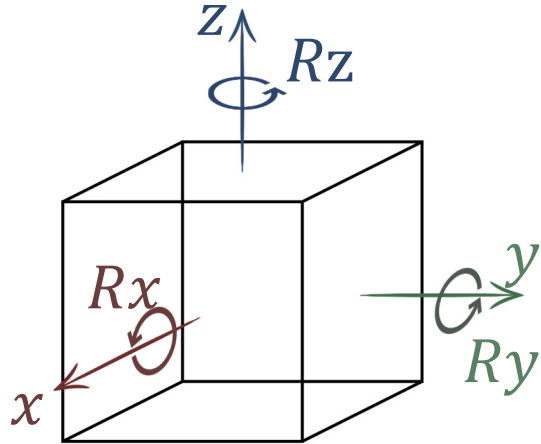
$$k_{eff} = \left(\frac{1}{k_1} + \frac{1}{k_2} \right)^{-1}$$



Dominated by the weakest element

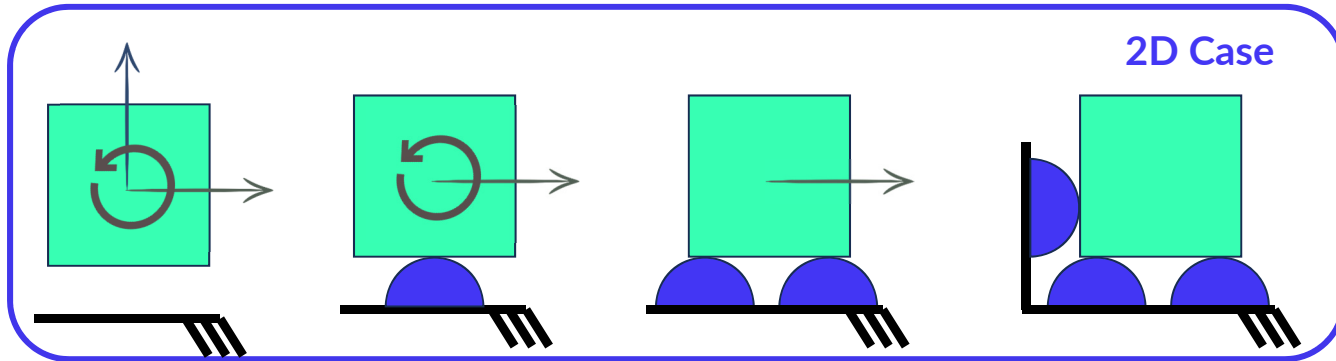
$$(k_{eff} < \min(k_1, k_2))$$

2.3. Mechanical: Control of Degrees of Freedom (DoF)

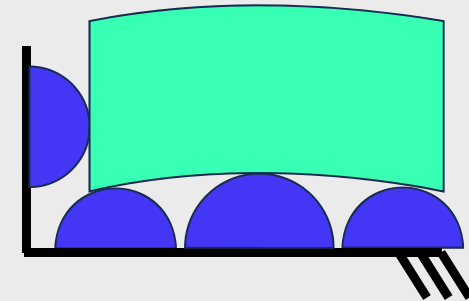
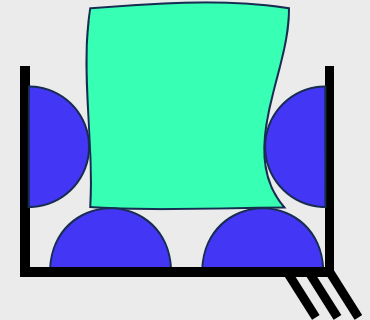


Restriction of Degrees of Freedom
by single-point contact:

- Hertz contact theory
- Friction/preload based
- Limited stiffness



Overconstraining
=
deformation



2.3. Mechanical: Bearings

and many others...



Ball Bearings



[SKF]



Roller Bearings

Needle Bearings

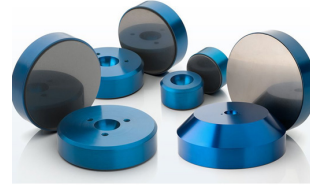


Linear Air Bushings

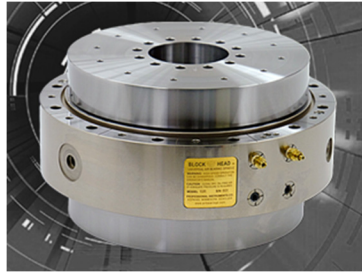


[Newway]

Flat Air Bushings

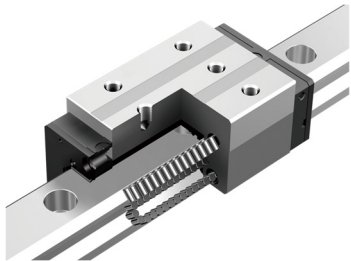


Air Bearing Spindles

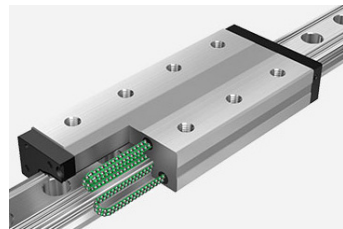


[Professional Instruments]

Needle Linear Guides



[THK]



Ball Linear Guides



[SKF]

Linear Ball Bush

Critical aspects

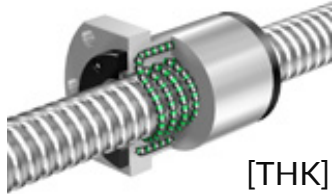
- Stiffness
- Motion errors
- Lubrication
- Friction
- Preload
- Noise levels
- Non-linearities
- Vacuum compatibility
- Temperature compatibility

2.3. Mechanical: Transmissions

and many others...



Ball Bearings



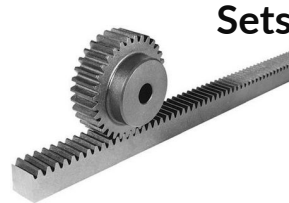
[THK]

Screw Transmissions



[Rollvis]

Rack-Pinion

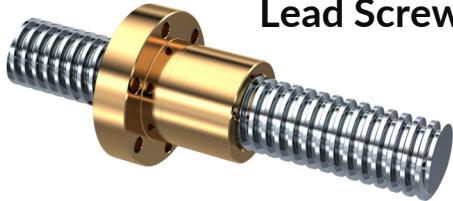


Sets

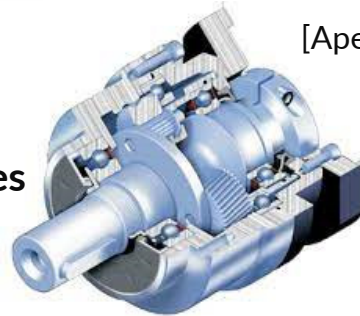
[Apex]

Square/Trapezoidal

Lead Screw

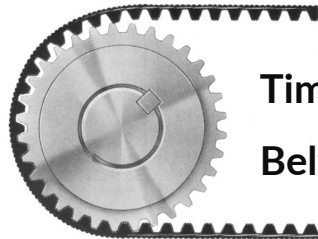


Gearboxes

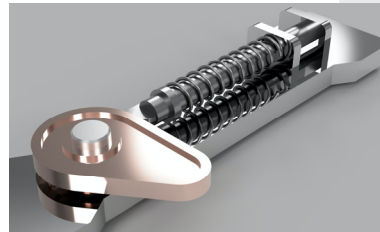


Worm-gear

sets



Timing Belts



Cams

[Autodesk]

Critical aspects

- Stiffness
- Efficiency
- Lubrication
- Friction
- Preload
- Noise levels
- Non-linearities
- Vacuum compatibility
- Temperature compatibility

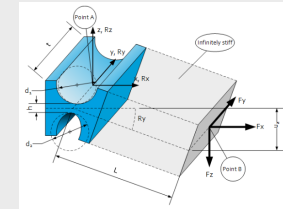
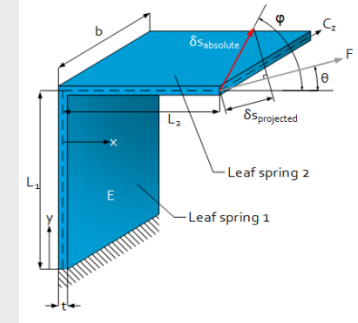
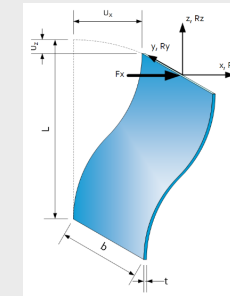
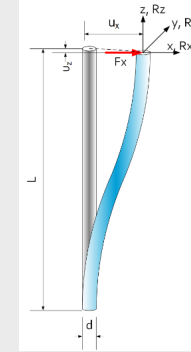
2.3. Mechanical: Flexural Mechanisms

PROs

- Predictable behavior/modeling
- Less dependent of friction
- Higher repeatability and resolution (reduced friction effects)
- Free of lubrication
- Lower (or negligible) level of maintenance

CONs

- Limited motion range
- Limited load capacity
- Non-linear behavior



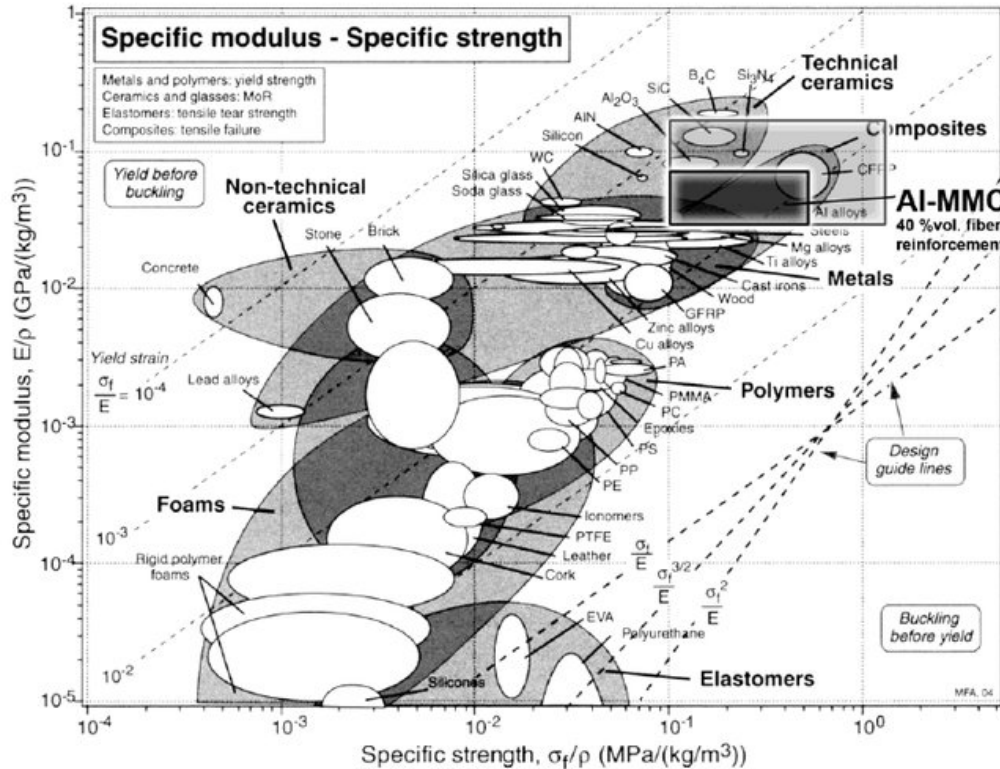
Images by:



Driven by innovation

<https://www.jpe-innovations.com/precision-point/>

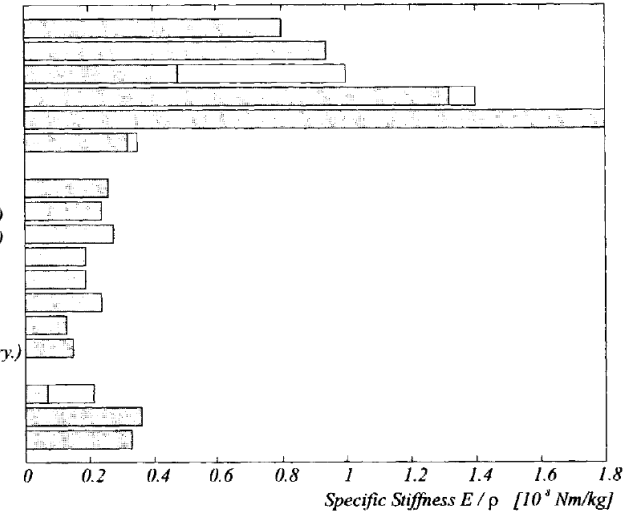
2.3. Mechanical: Material Properties



Al₂O₃
AlN
Si₃N₄
SiC
B₄C
ZrO₂

Steel
Steel (N129)
Steel (N219)
Invar
Super Invar
Al (T633)
Copper
Copper (Bery.)

Granite
Zerodure
Silica



T. Ruijl (2001)

Parameters of interest:

- Elastic modulus
- Yield strength
- Density
- Vacuum compatibility

2.3. Mechanical: Actuators

and many others...



Piezo Stacks



Voice-coil Actuators



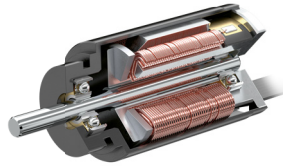
Critical aspects

- Actuation principle
- Force levels
- Actuation range
- Noise levels
- Non-linearities
- Vacuum compatibility
- Temperature compatibility

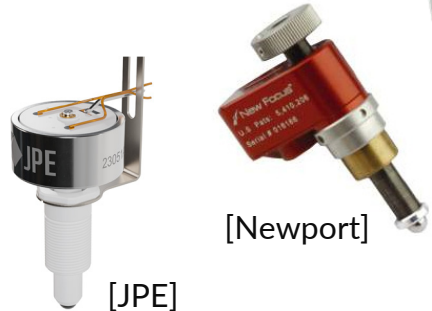
Piezo Walkers



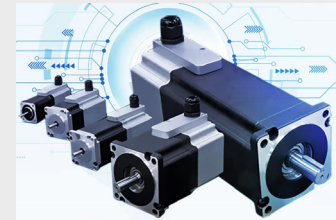
Stepper Motors



Picomotors



Linear Motors



Servo Motors

2.3. Mechanical: Sensors

and many others...



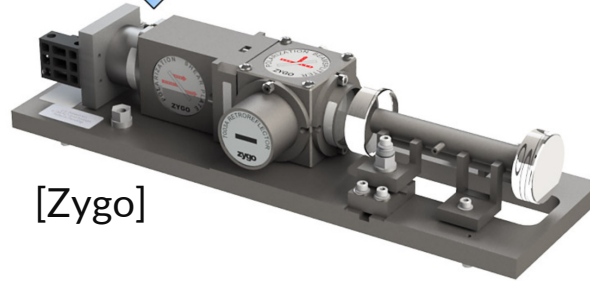
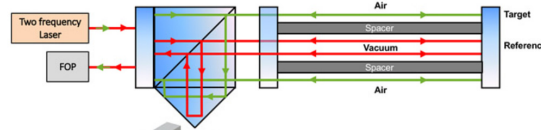
CNPEM

Capacitive Probes



[Lion/IBS]

Laser Interferometers



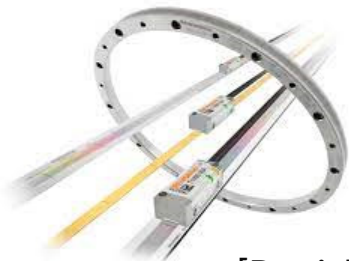
[Zygo]

Accelerometers

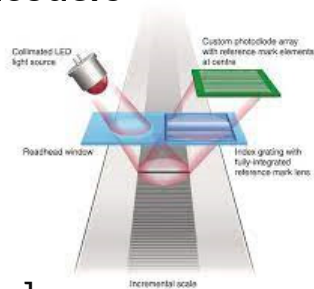


[Kistler]

Optical Encoders



[Renishaw]



Critical aspects

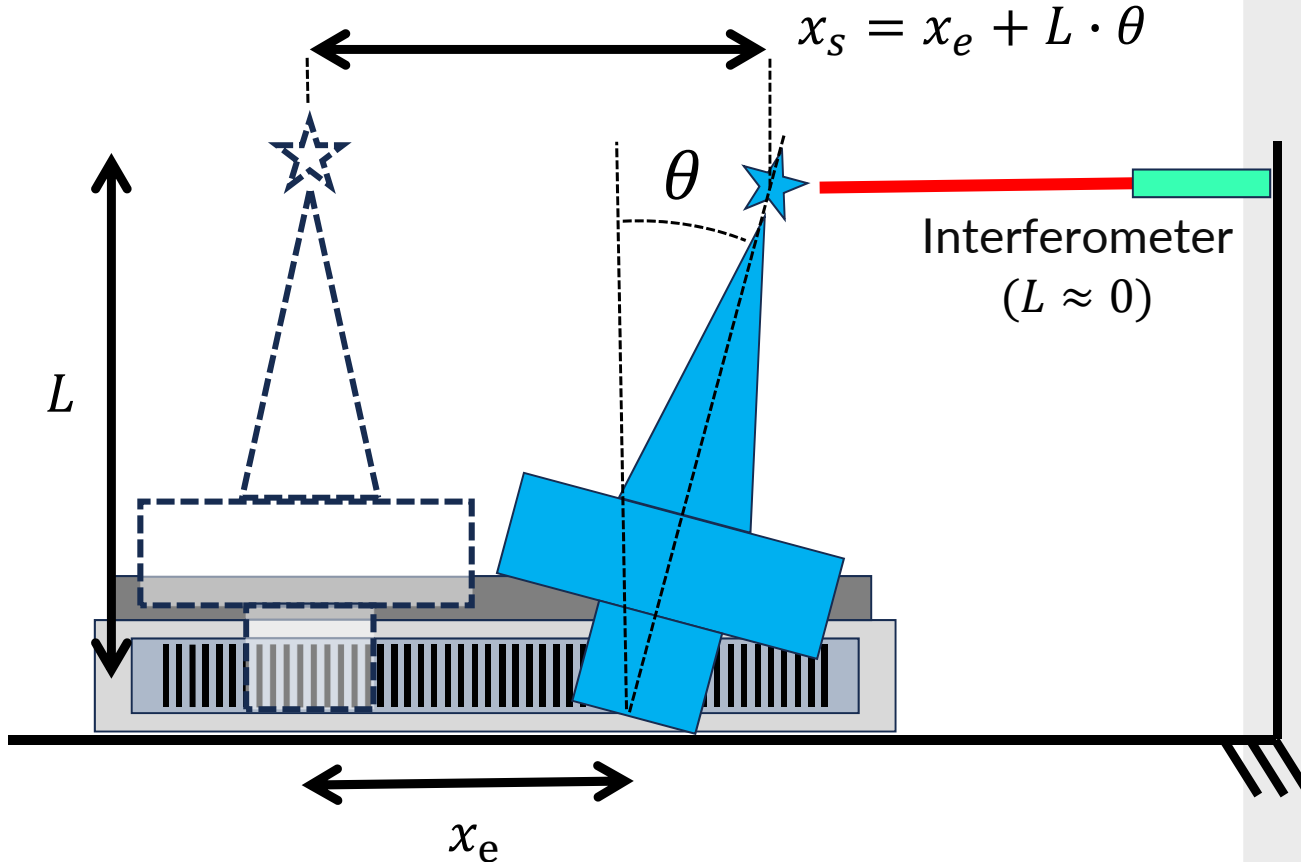
- Absolute vs Relative
- Measurement range
- Communication protocol
- Measurement bandwidth
- Noise levels
- Non-linearities
- Vacuum compatibility
- Temperature compatibility

Autocollimator



[Möller Wedel]

2.3. Mechanical Metrology: Abbé



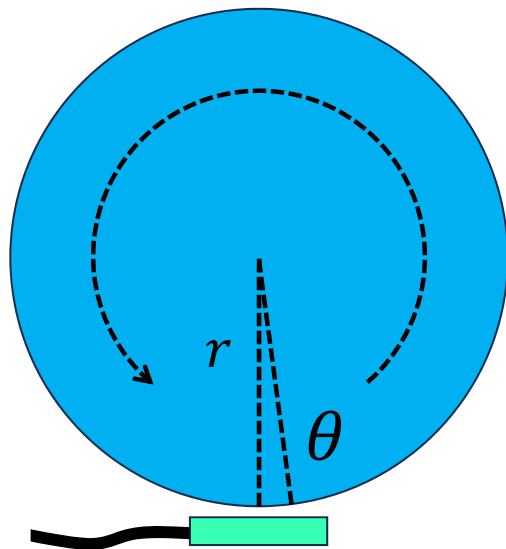
E.g.:

- $L = 25 \text{ mm}$
- $\theta = 1 \mu\text{rad}$
- $\epsilon = 25 \text{ nm!}$

Options:

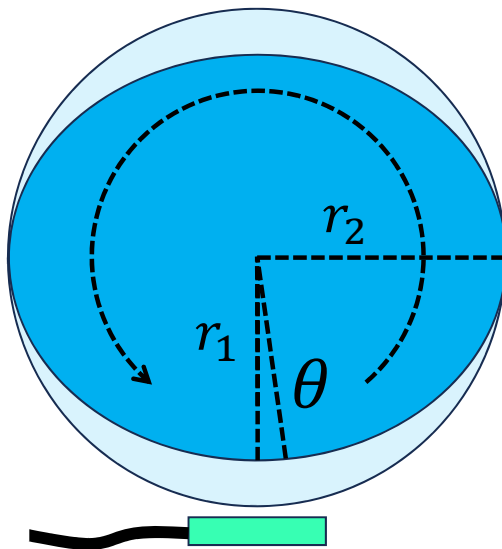
- Reduction of lever-arms as much as possible;
- Measurement of additional DoFs;
- Calibration.

2.3. Mechanical Metrology: Angular Measurements



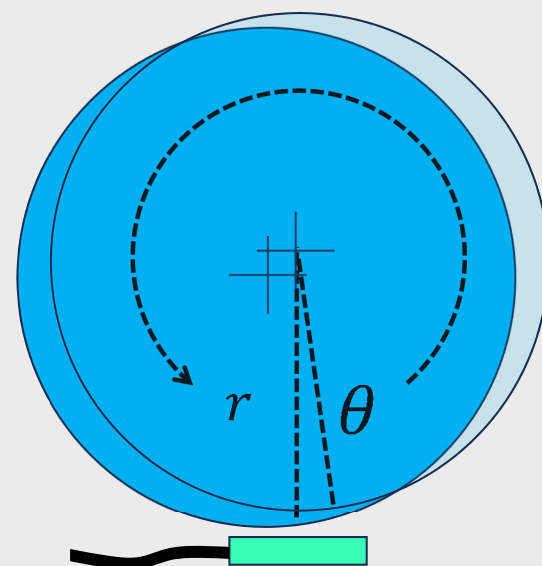
Encoder Head

$$\theta = x_e / r$$



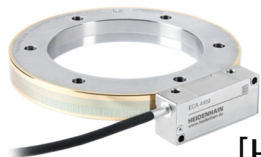
Encoder Head

$$\theta = x_e / r(\theta)$$



Encoder Head

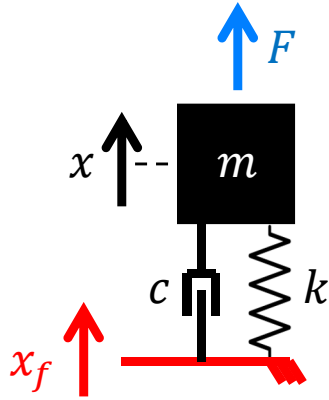
$$\theta = x_e / r(\theta)$$



[Heidenhain]

*Options: use of multiple heads, calibration, etc.

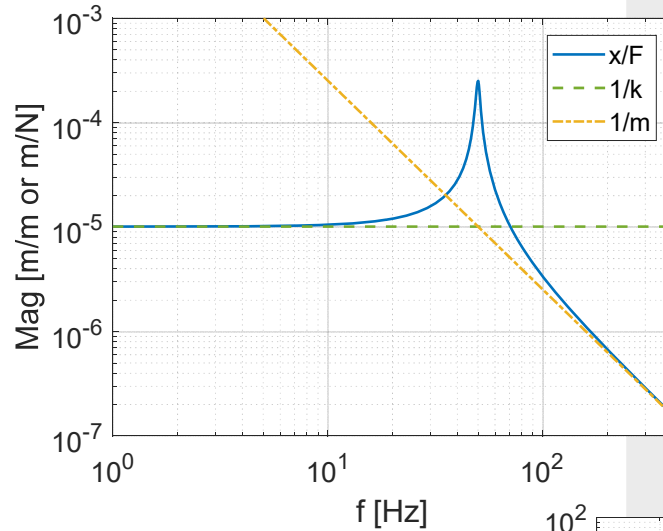
2.4. Dynamics



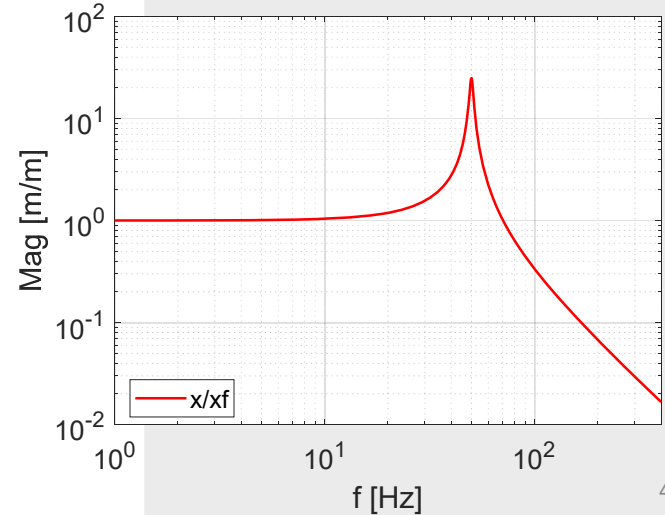
$$m\ddot{x} + c\dot{x} + kx = F + c\dot{x}_f + kx_f$$

↓ Laplace's Transform

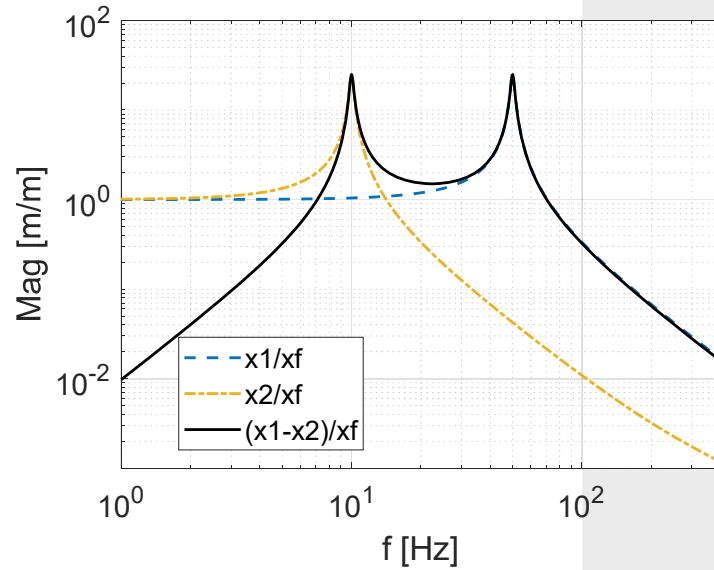
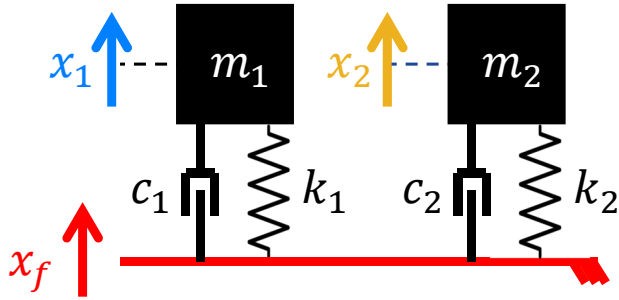
$$ms^2x + csx + kx = F + csx_f + kx_f$$



- Shift peaks beyond disturbance sources
- Work on damping (when possible)

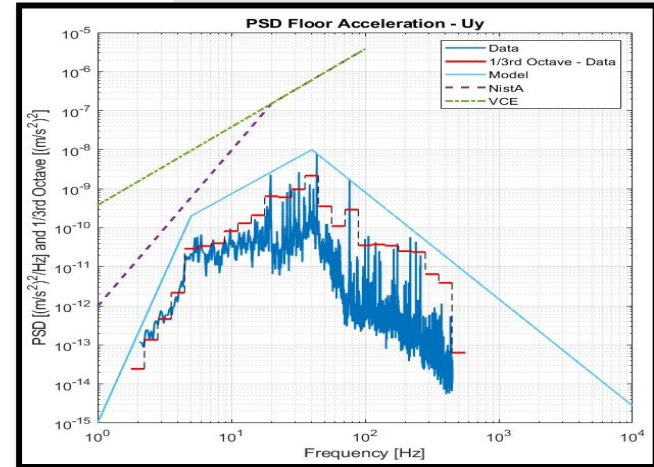


2.4. Dynamics



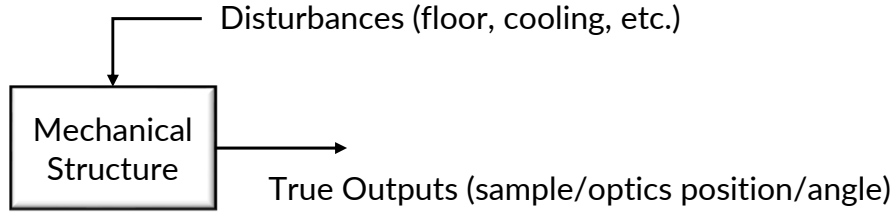
E.g.:

- m1: lens (50 Hz)
- m2: sample (10 Hz)

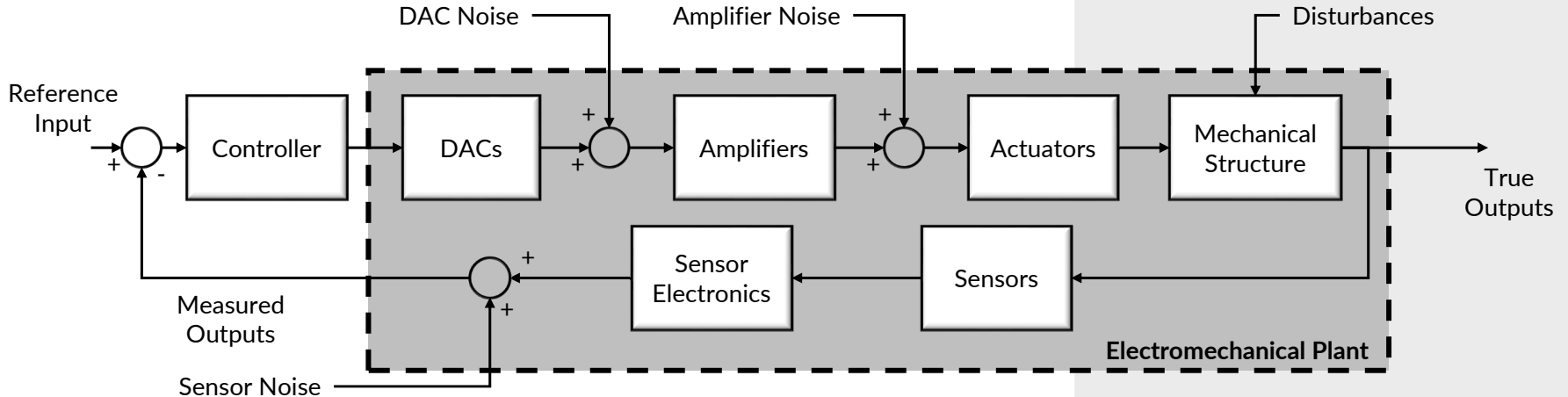


2.4. Dynamics: Control

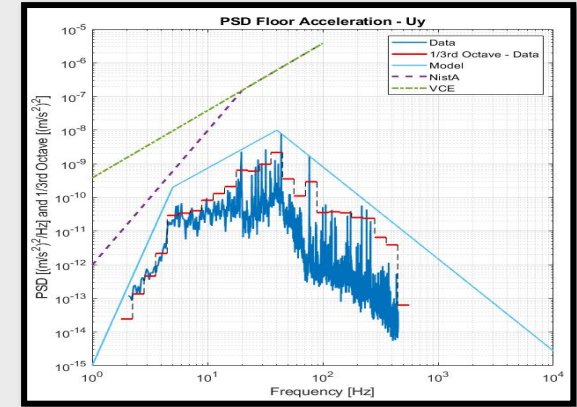
Passive approach:



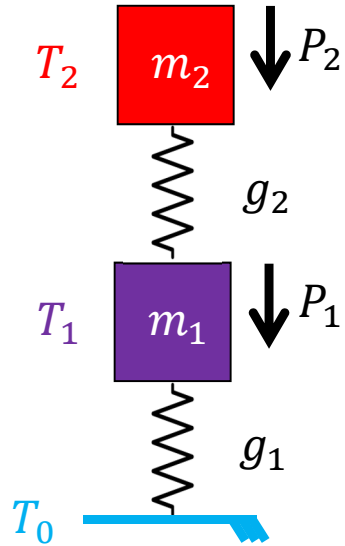
Active approach:



Example:

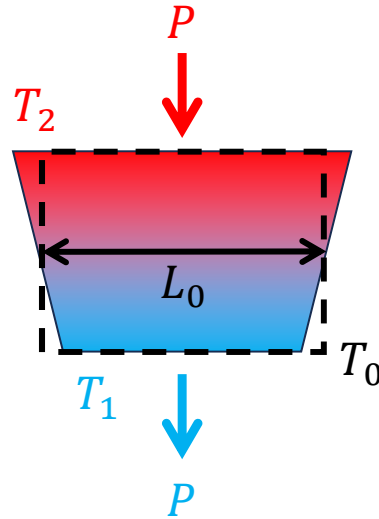


2.5. Thermal: Fundamentals



Stead-state approximation:

$$P = g \cdot \Delta T$$



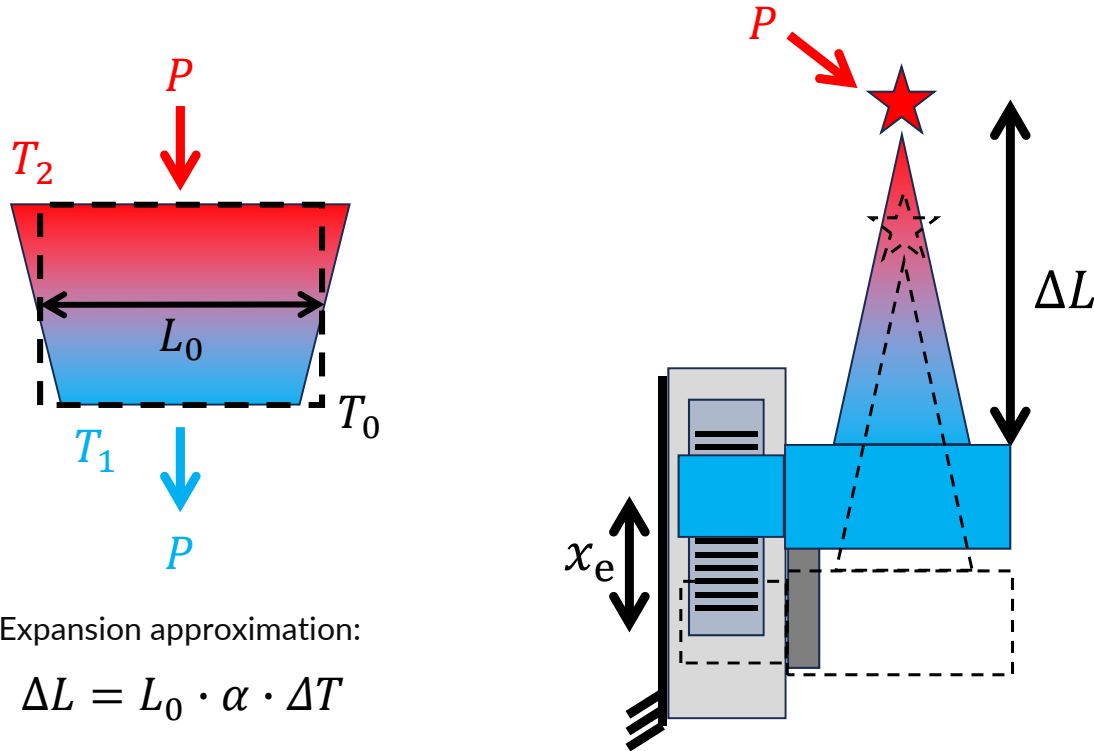
Expansion approximation:

$$\Delta L = L_0 \cdot \alpha \cdot \Delta T$$

Critical aspects:

- **Heat sources:** beam, motors, sensors, environment, people ...
- **Heat transfer mechanisms:** conduction, convection and radiation
- **Thermal expansion effects**
- **Measurements**

2.5. Thermal: Fundamentals

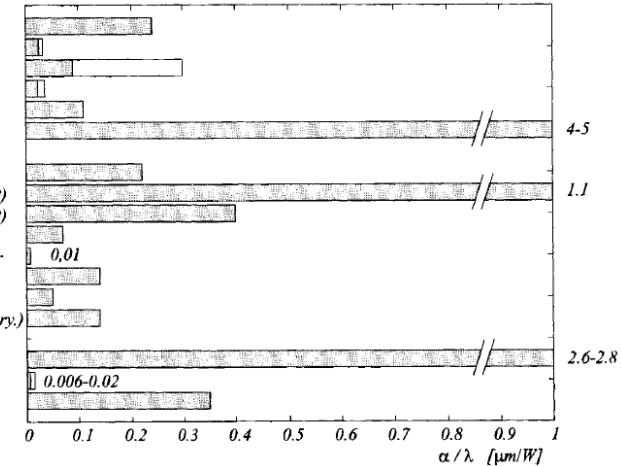
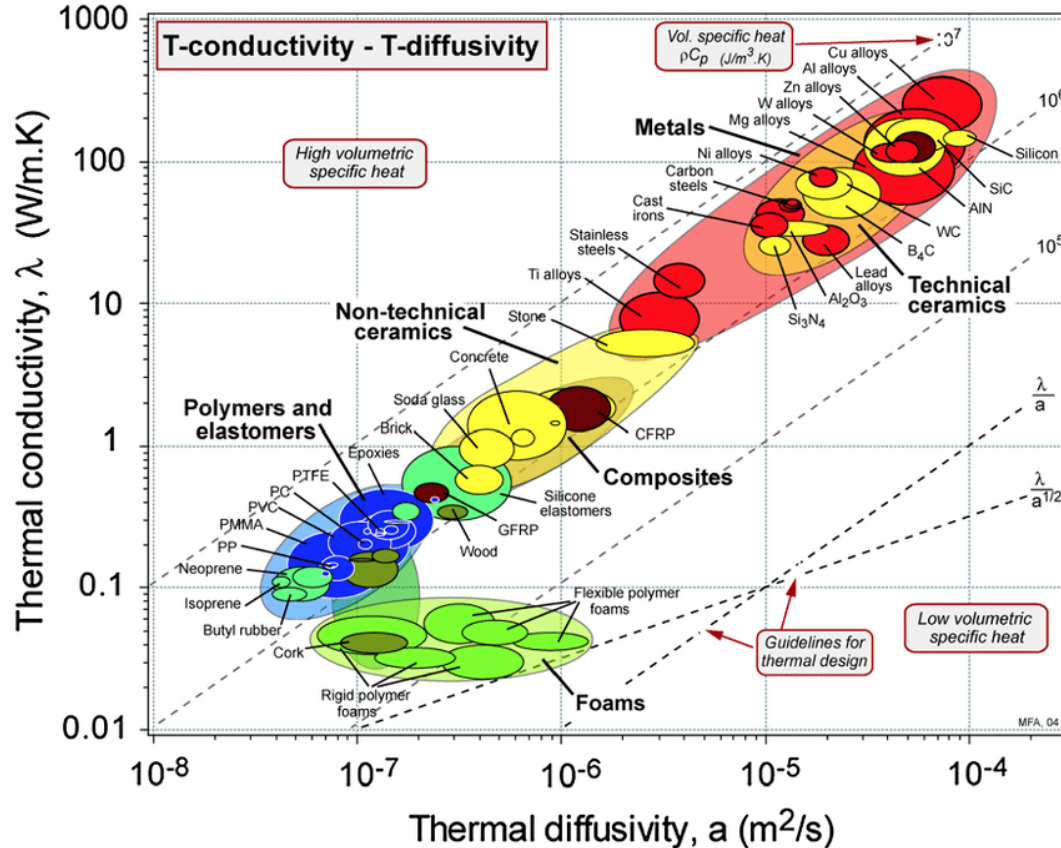


E.g.:

- $L = 25 \text{ mm}$
- $\Delta T = 0.1 \text{ K}$
- $\alpha = 20 \mu\text{m}/\text{m}\cdot\text{K}$ (Al)
- $\Delta L = 50 \text{ nm!}$

2.6. Thermal: Material Properties

Bending Sensitivity



T. Ruijl (2001)

Parameters of interest:

- Coefficient of thermal expansion (α)
- Thermal conductivity (λ)
- Coefficient of heat capacity (c_p)
- Density (ρ)

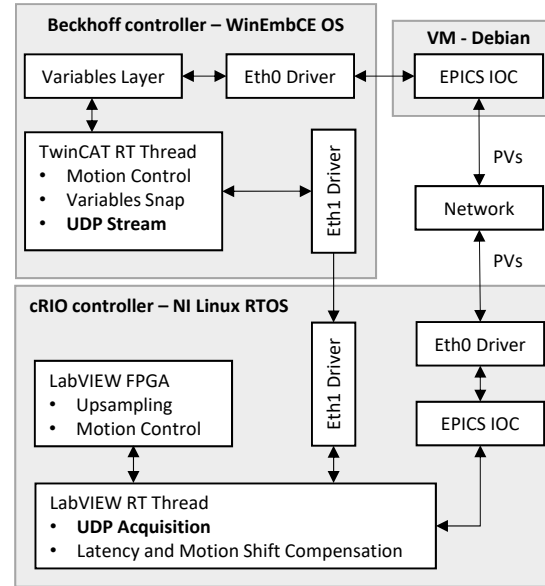
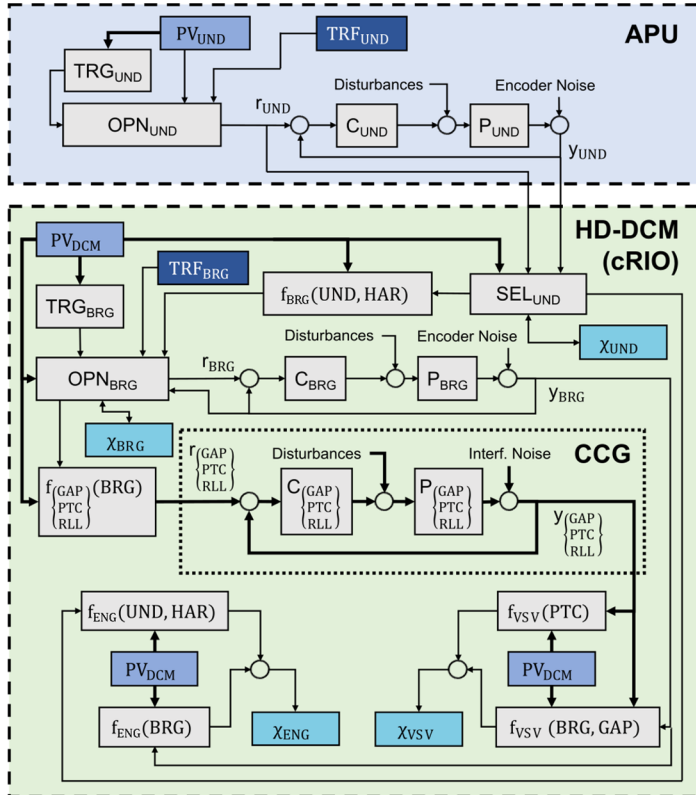
(doi: 10.1007/s10704-020-00487-7) [$\lambda/(\rho \cdot c_p)$ (temperature wavefront propagation)]

3. Beamline Integration

3.1. Double-Crystal Monochromator

3.2. Scanning Microscopes

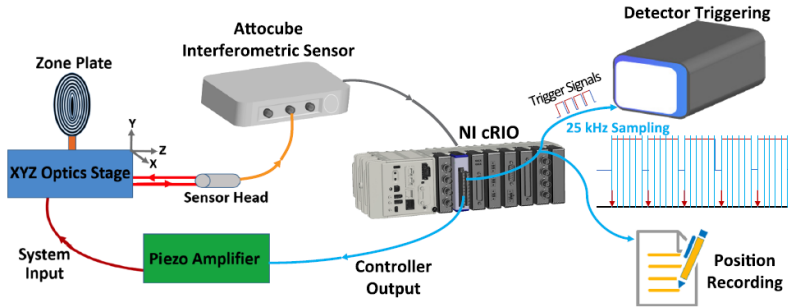
2.6. Integration: DCM (spectroscopy)



Critical aspects:

- Multiple instruments
- Master-follower architecture
- Different dynamic performances
- Different protocols
- kHz rates
- Synchronization
- Matching trajectories
- Control complexity

2.6. Integration: Scanning Microscopes

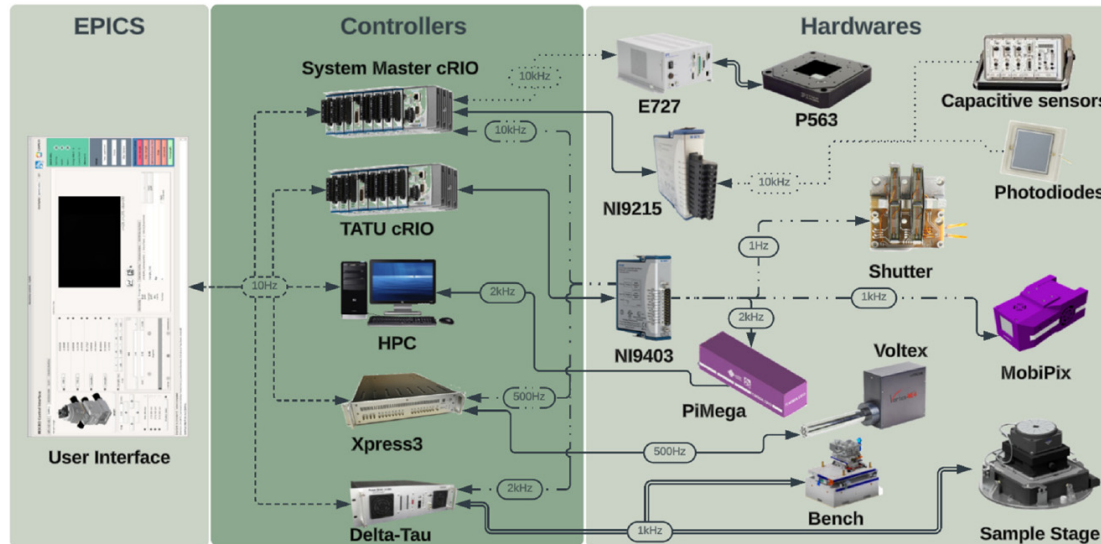


(doi: 10.1063/1.5103173)

(doi: 10.1016/
j.elspec.2023.147340)

Critical aspects:

- Multiple instruments
- Multiple protocols
- Central orchestrator
- kHz rates
- Synchronization
- Control complexity
- Trajectory optimization
- Software complexity
- Data storage
- Data processing



Outline: Nanopositioning

- Introduction
- Motivation
- Commercial Scenario
- Development Framework
- **Examples at Sirius**
- Conclusions & Perspectives

1. HD-DCM

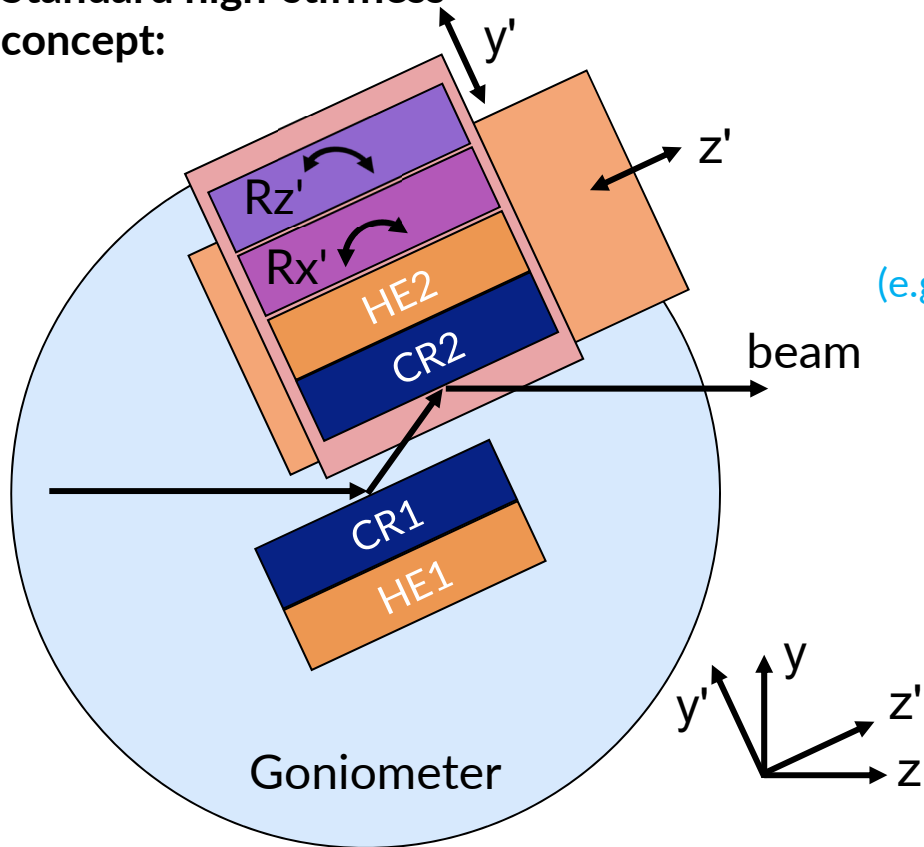
2. Mirrors

3. Nanoprobes

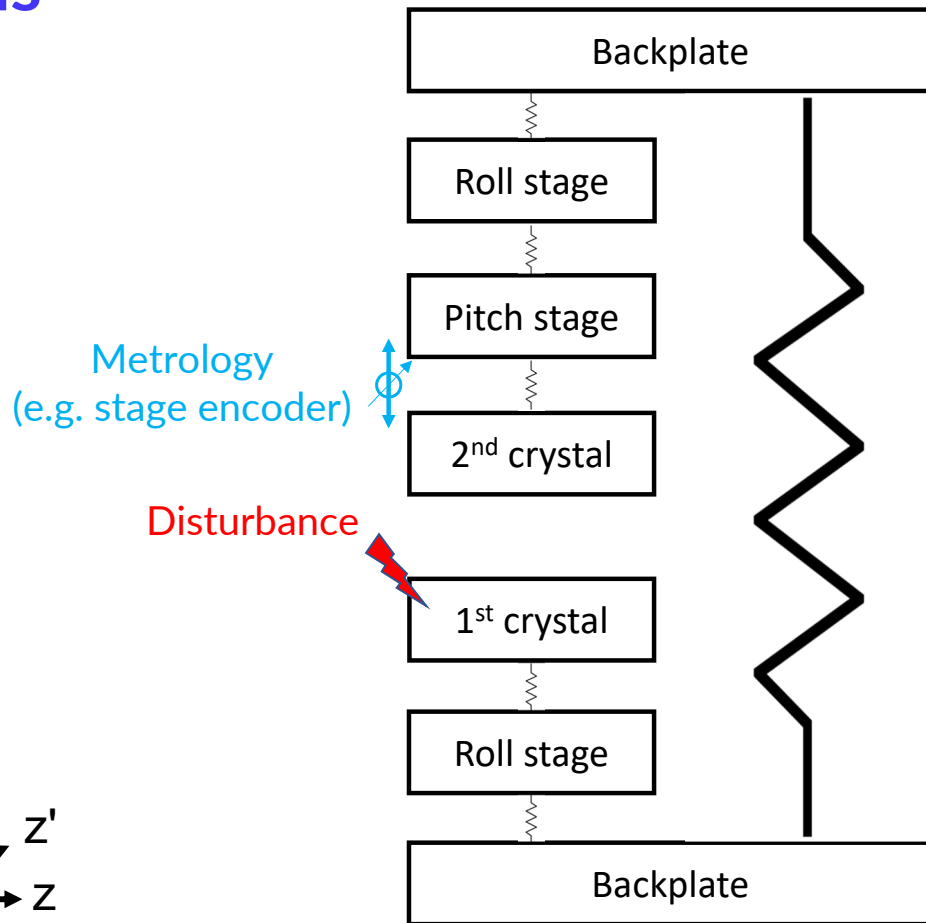
1. The HD-DCM

1. Standard DCM Designs

Standard high-stiffness concept:

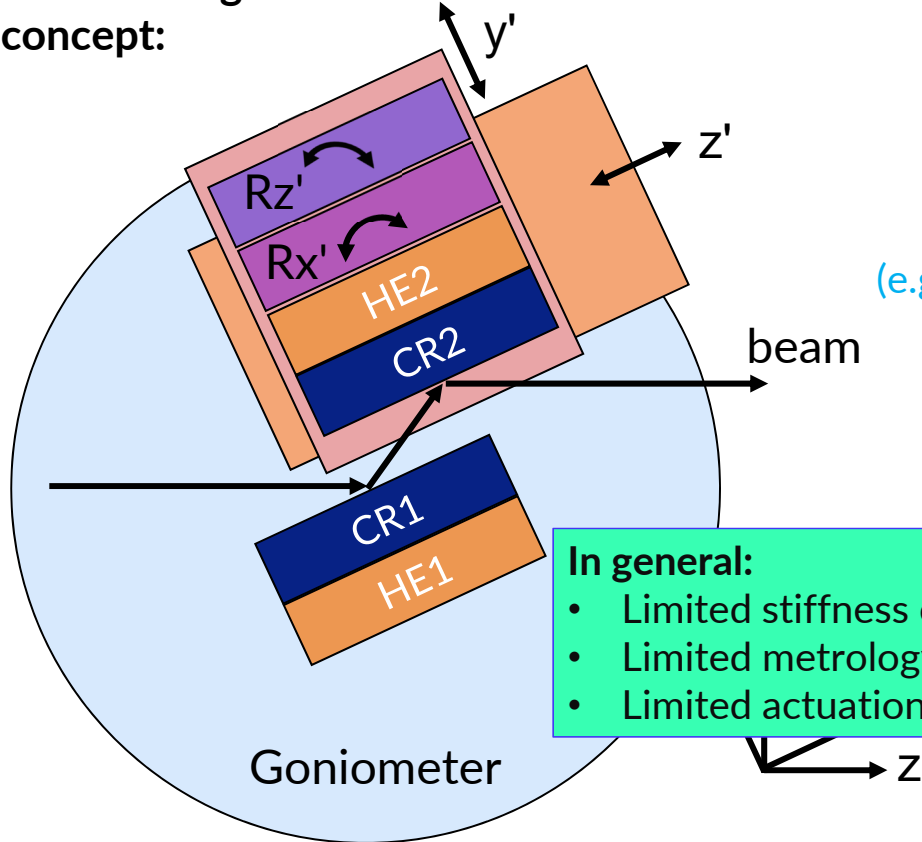


Illustrative 1D Pitch Stiffness Model



1. Standard DCM Designs

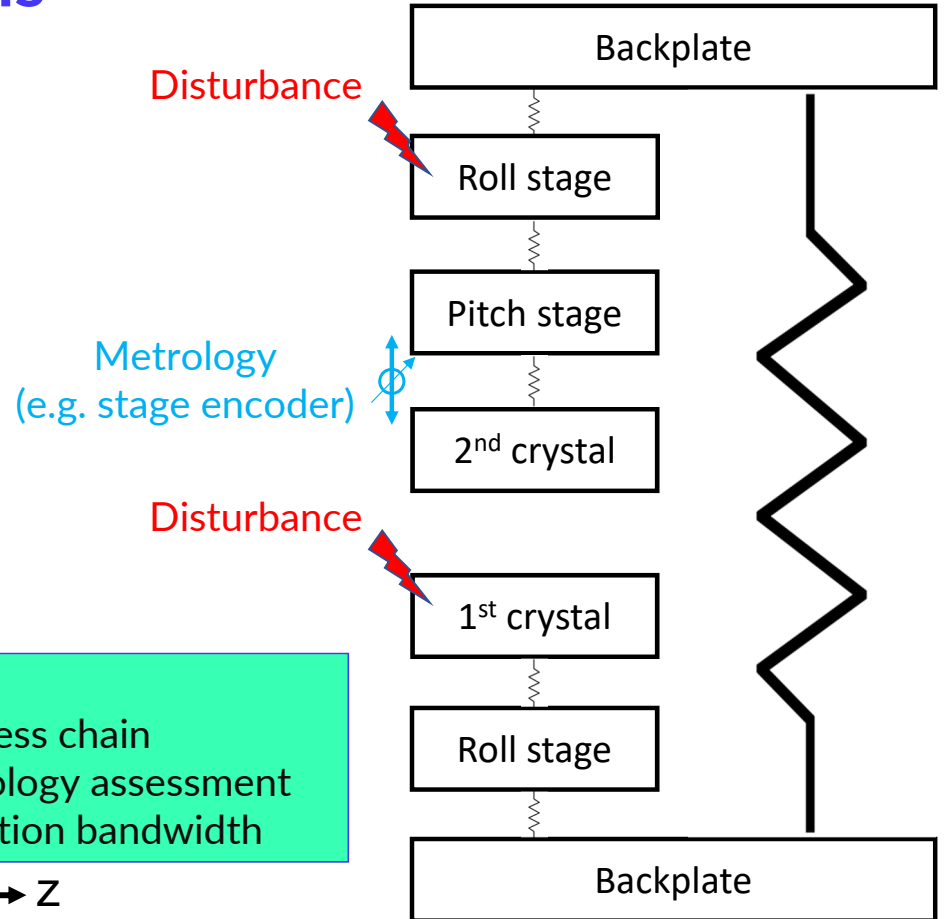
Standard high-stiffness concept:



In general:

- Limited stiffness chain
- Limited metrology assessment
- Limited actuation bandwidth

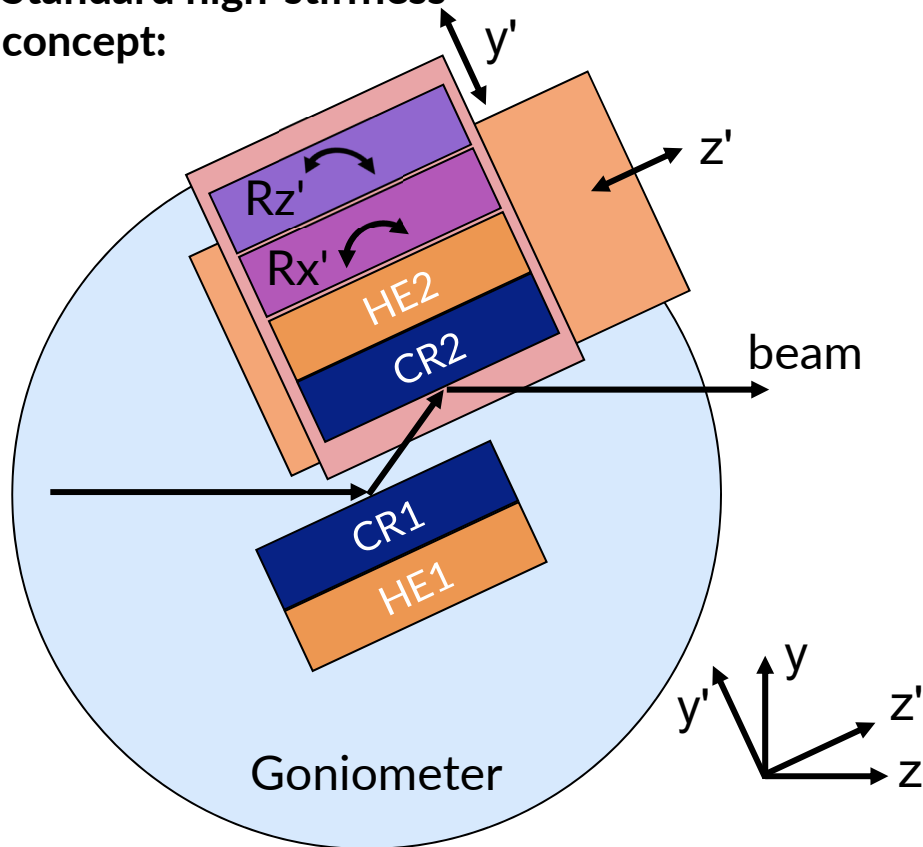
Illustrative 1D Pitch Stiffness Model



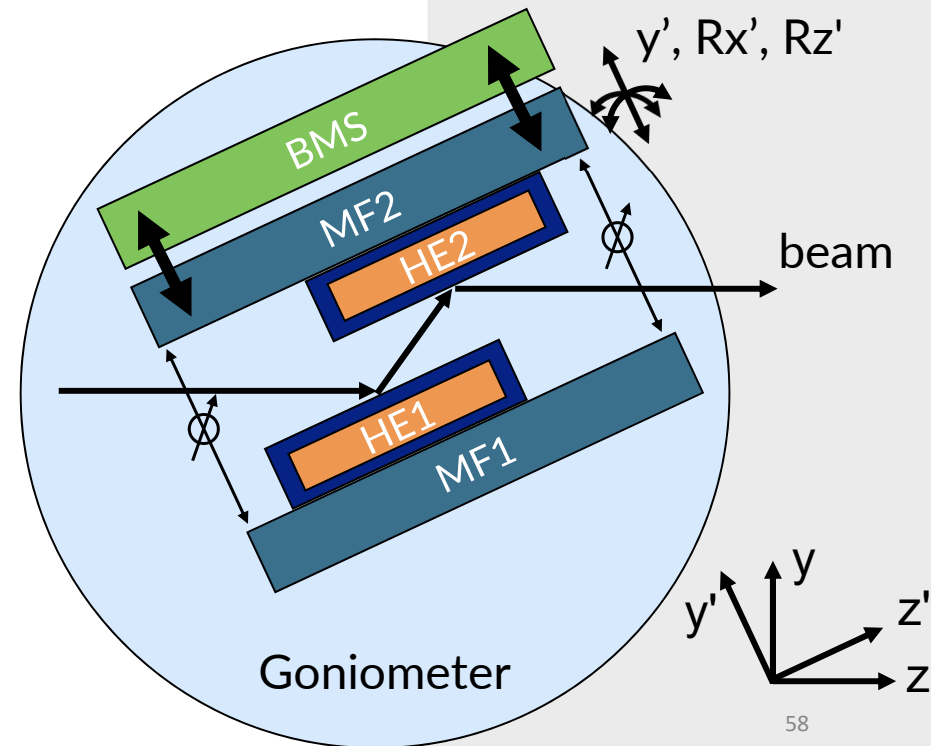
1. DCM Architecture Comparison

(doi:10.1088/1742-6596/2380/1/012050)

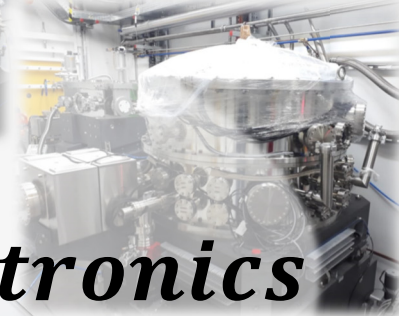
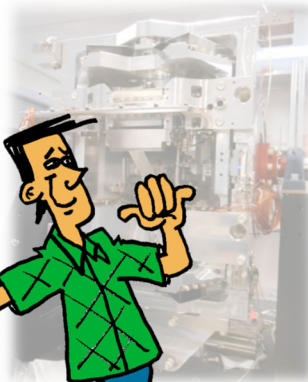
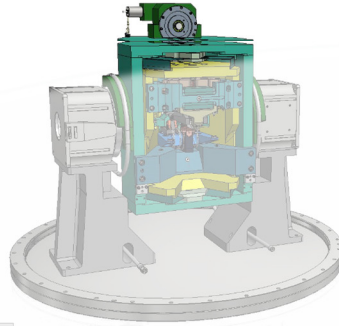
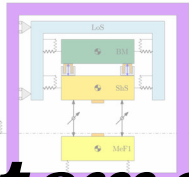
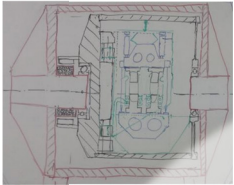
Standard high-stiffness concept:



HD-DCM mechatronic concept:



1. The HD-DCM Project Timeline



Automation

Mechatronics

03/2015
Kick-off

12/2015
Conceptual
Sketch

08/2016
Conceptual
Design

12/2016
Global
Design

02/2017
Detailed
Design

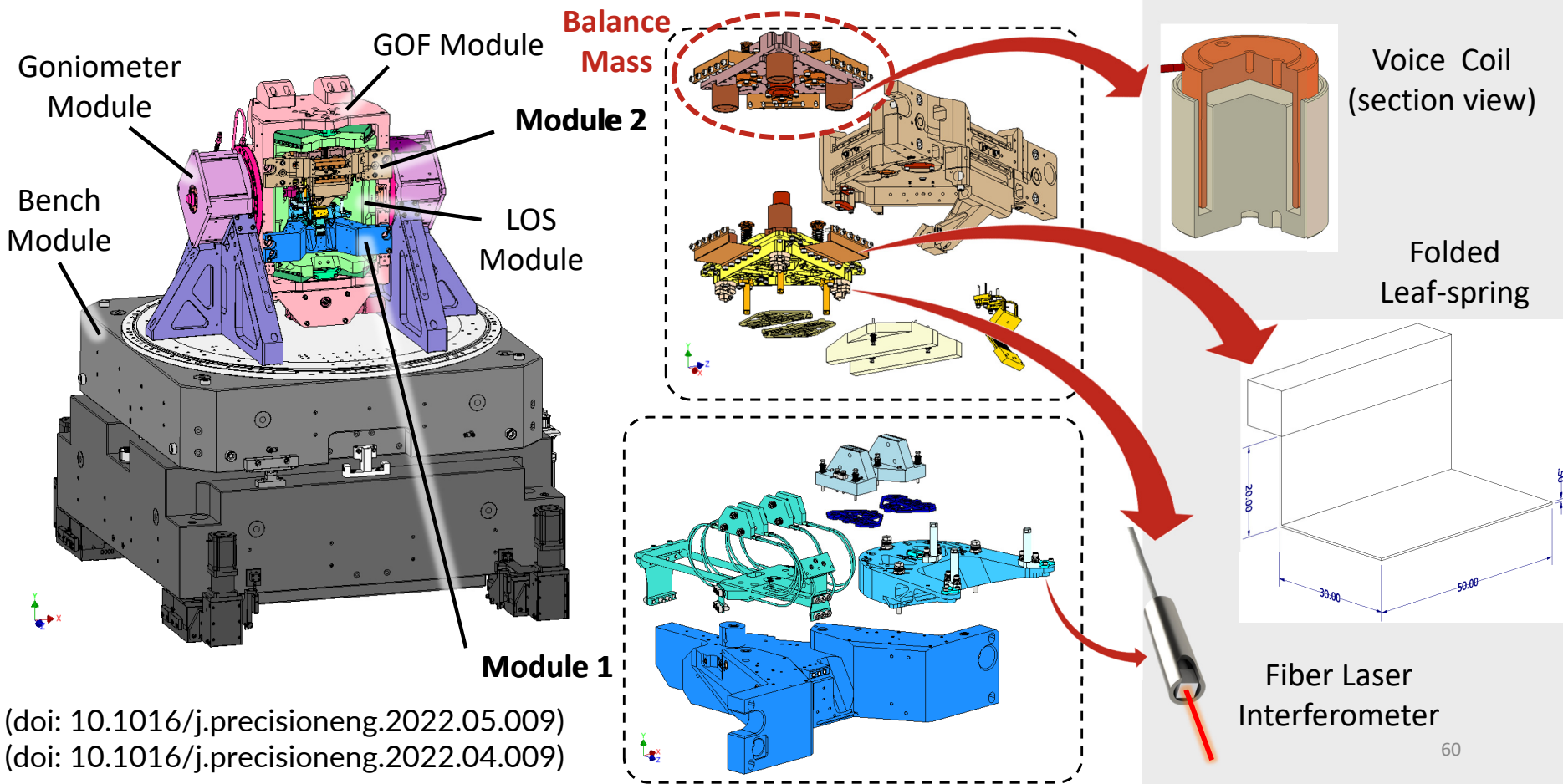
05/2017
Pre
Validation

05/2018
Offline
Validation

05/2020
Online
Validation

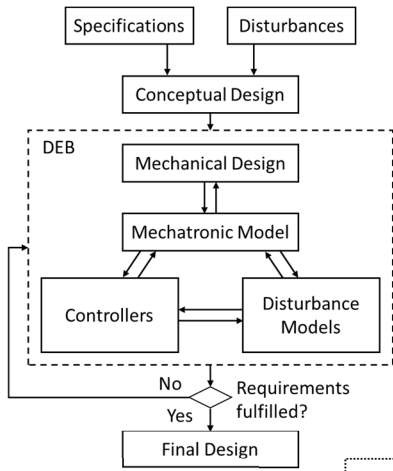


1. The HD-DCM Architecture

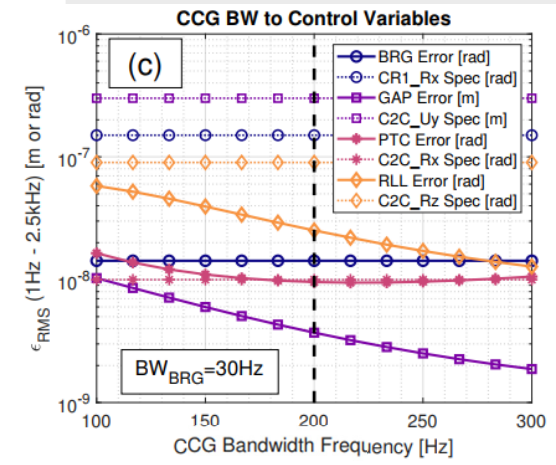
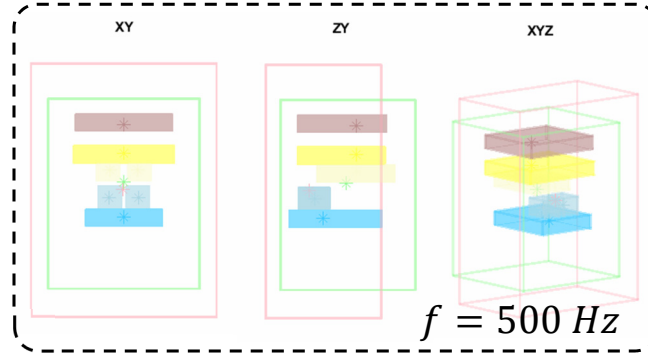


1. The HD-DCM Dynamic Error Budgeting

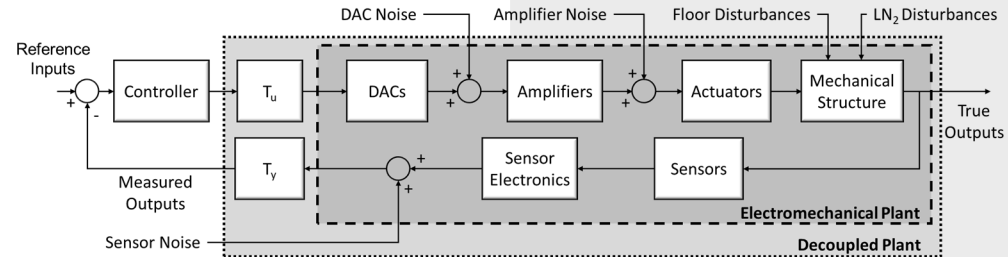
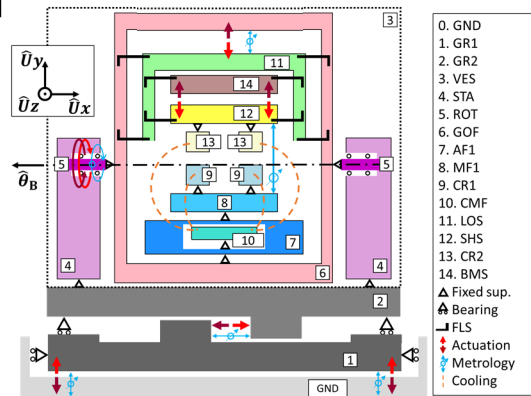
DEB Framework



Mode Shapes



Lumped Mass Model

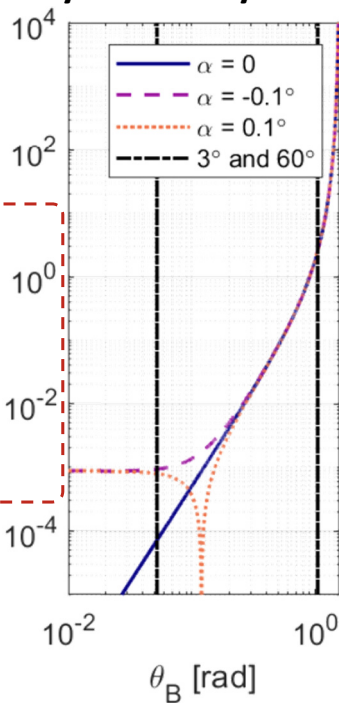


Feedback control loop schematic

1. The HD-DCM Beamline Integration

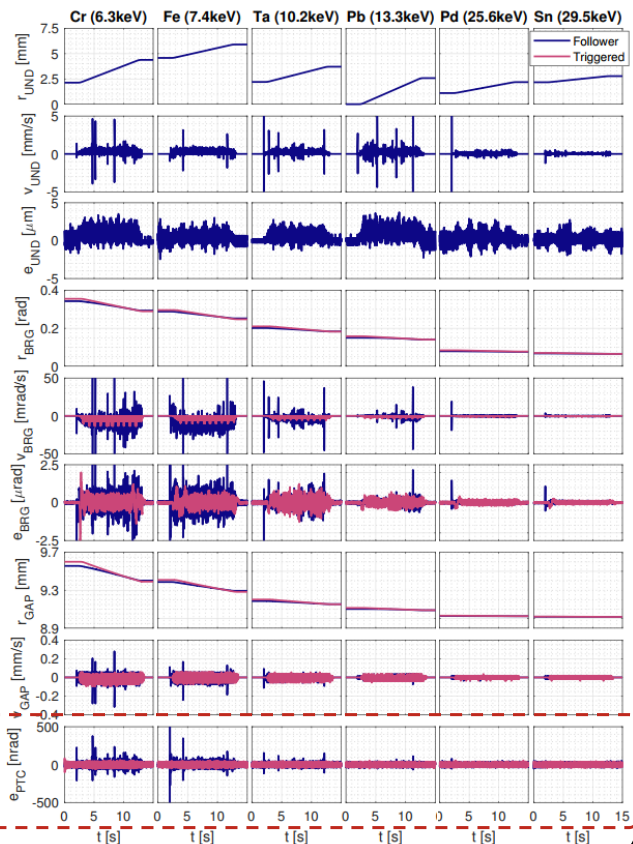


Flyscan Analysis

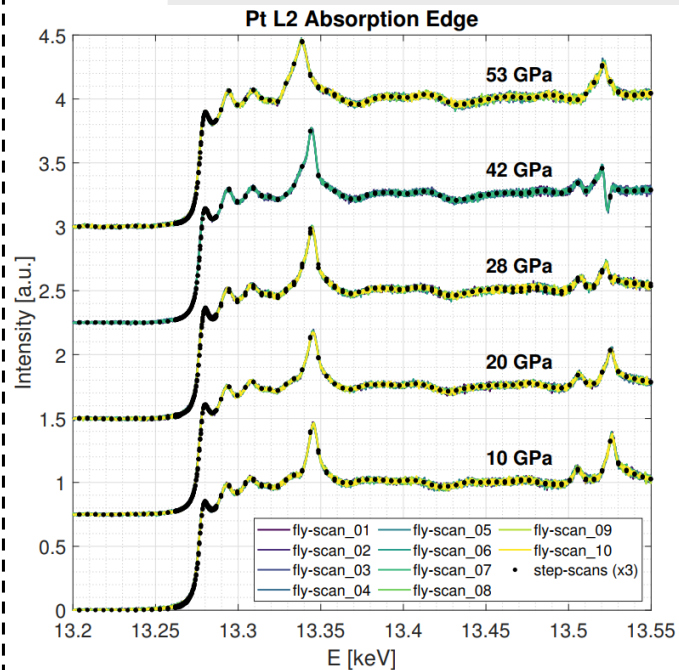


$$\frac{\partial g}{\partial t} = -\eta_2(\theta_B) \frac{2d}{nhc} \frac{H}{\cos(\alpha)} \frac{\partial E}{\partial t}$$

Undulator-DCM Integration



Flyscan vs Step-scan Experiment

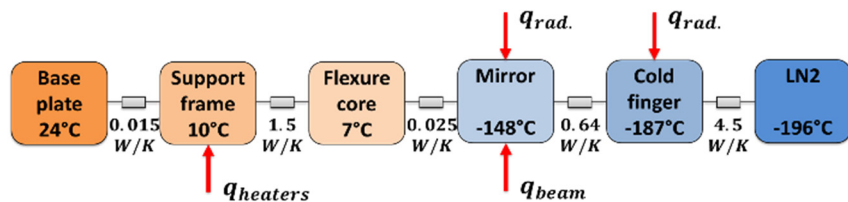
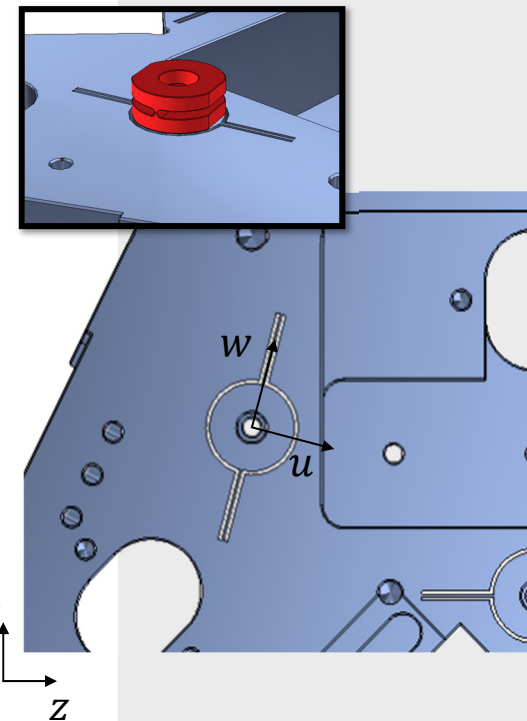
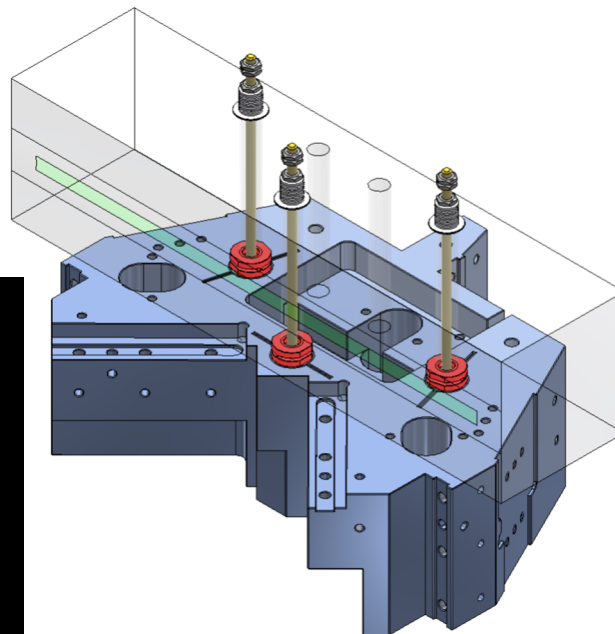


(doi: 10.1107/s1600577522010724)

2. Mirror Systems

2. (Quasi) Isostatic Mirror Fixation

Assembly
and
thermal expansion



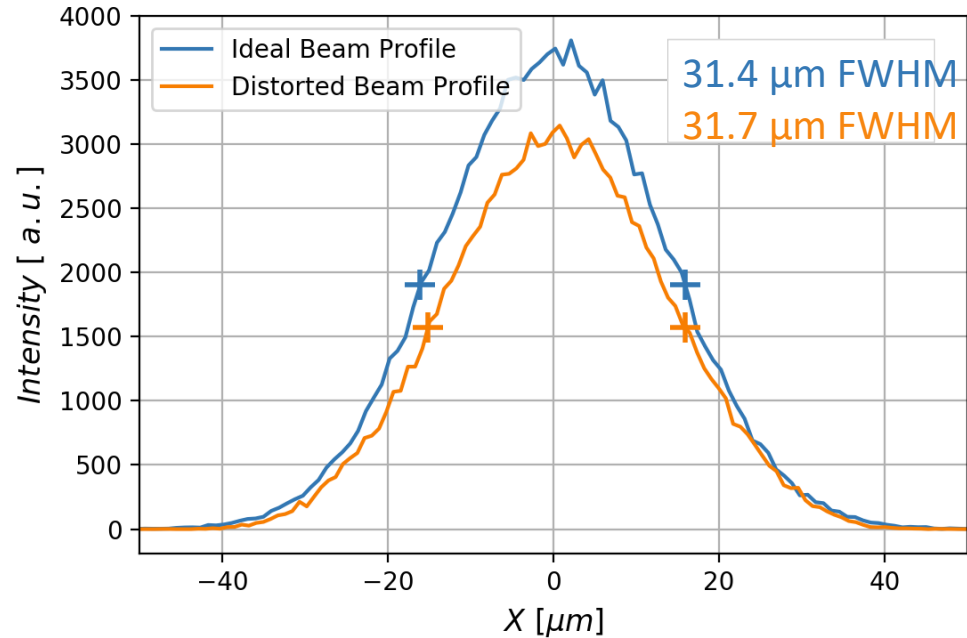
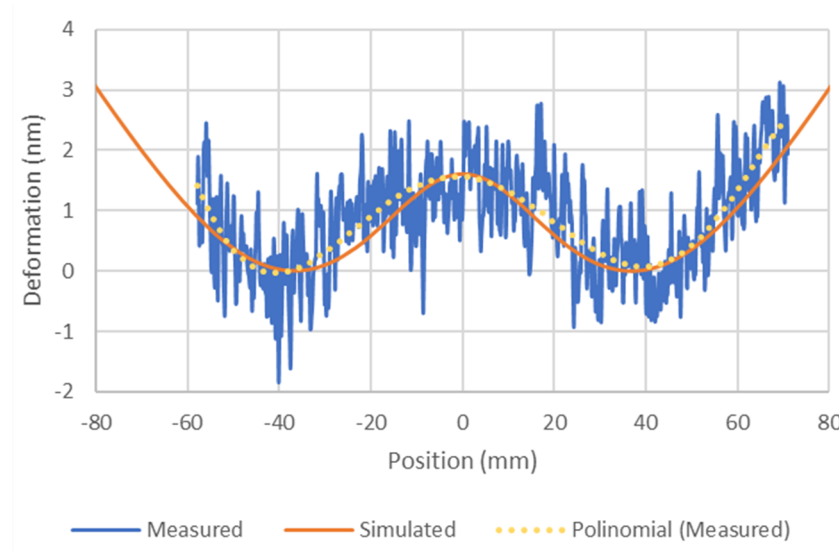
(doi: 10.1364/sxray.1991.the3)

(doi: 10.18429/JACoW-MEDSI2018-WEPH31)

2. Mirror Manufacturing and Fixation Effects

Beam Profile Simulations

Fizeau Measurements



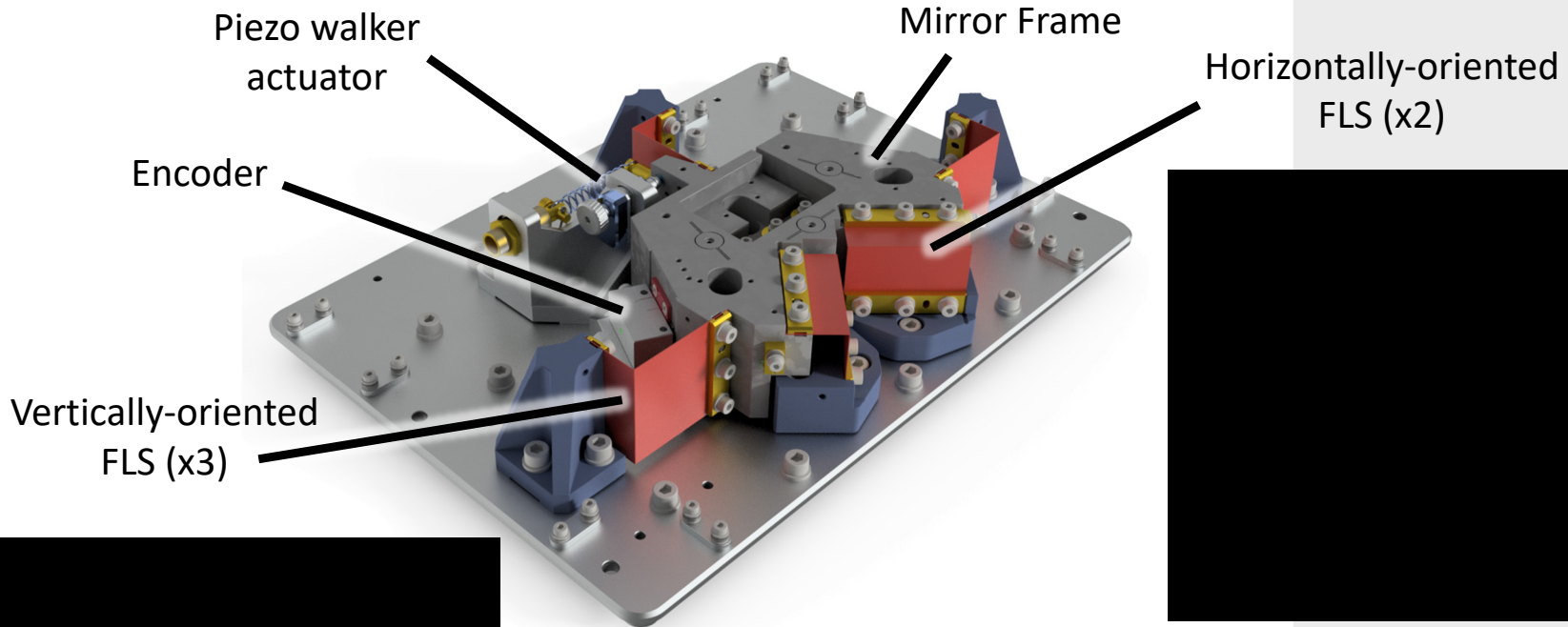
(doi: 10.1364/sxray.1991.the3)

(doi: 10.18429/JACoW-MEDSI2018-WEPH31)

- Gravity
- Thermal
- Bolt tightening

- Mirror polishing
- Manufacturing limitations

2. Mirror Isostatic Compliant Mechanism



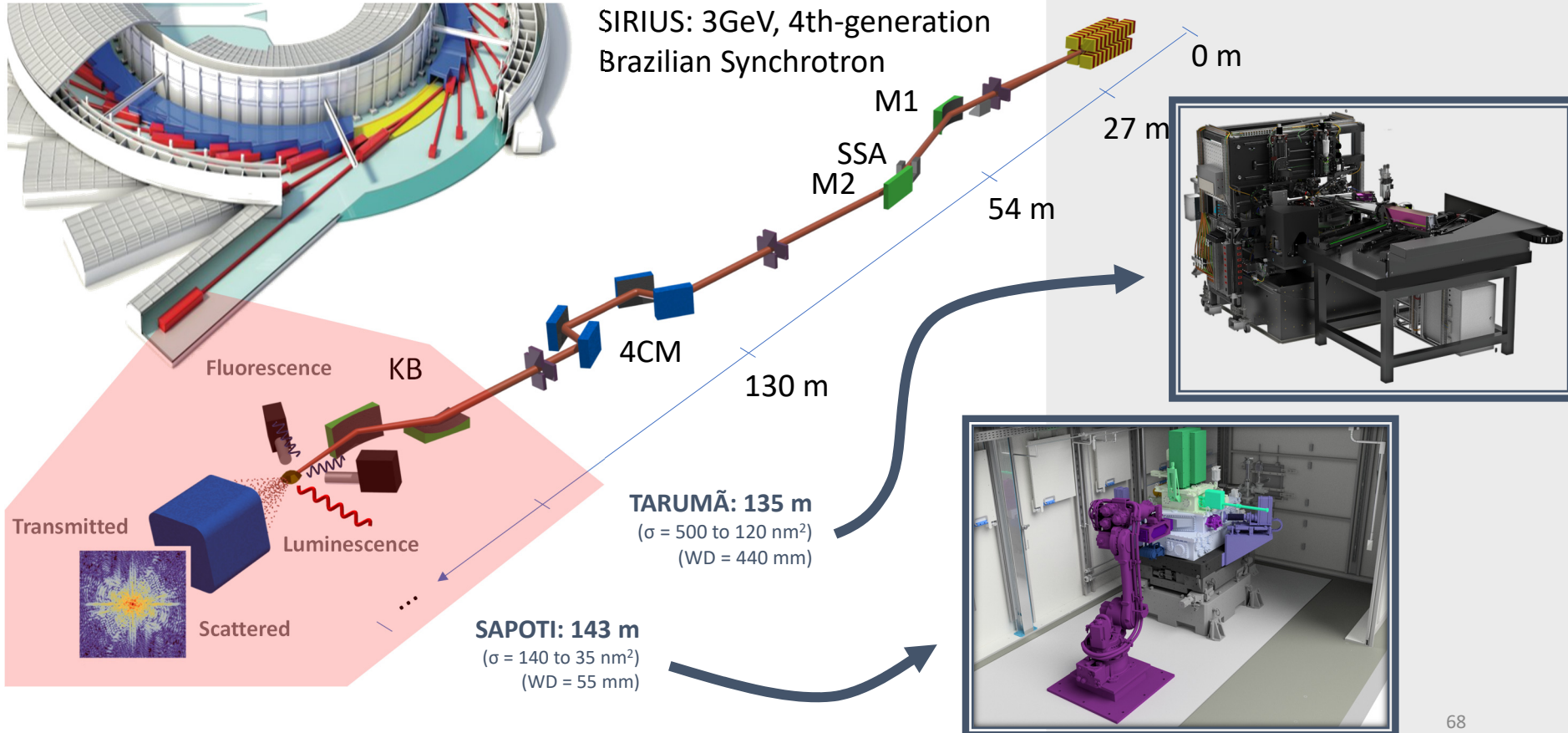
Mode	FEA [Hz]	Experimental [Hz]
1 (T_x)	249,7	250
2 (R_y)	312,5	313
3 (T_z)	342,4	341

3. Nanoprobes

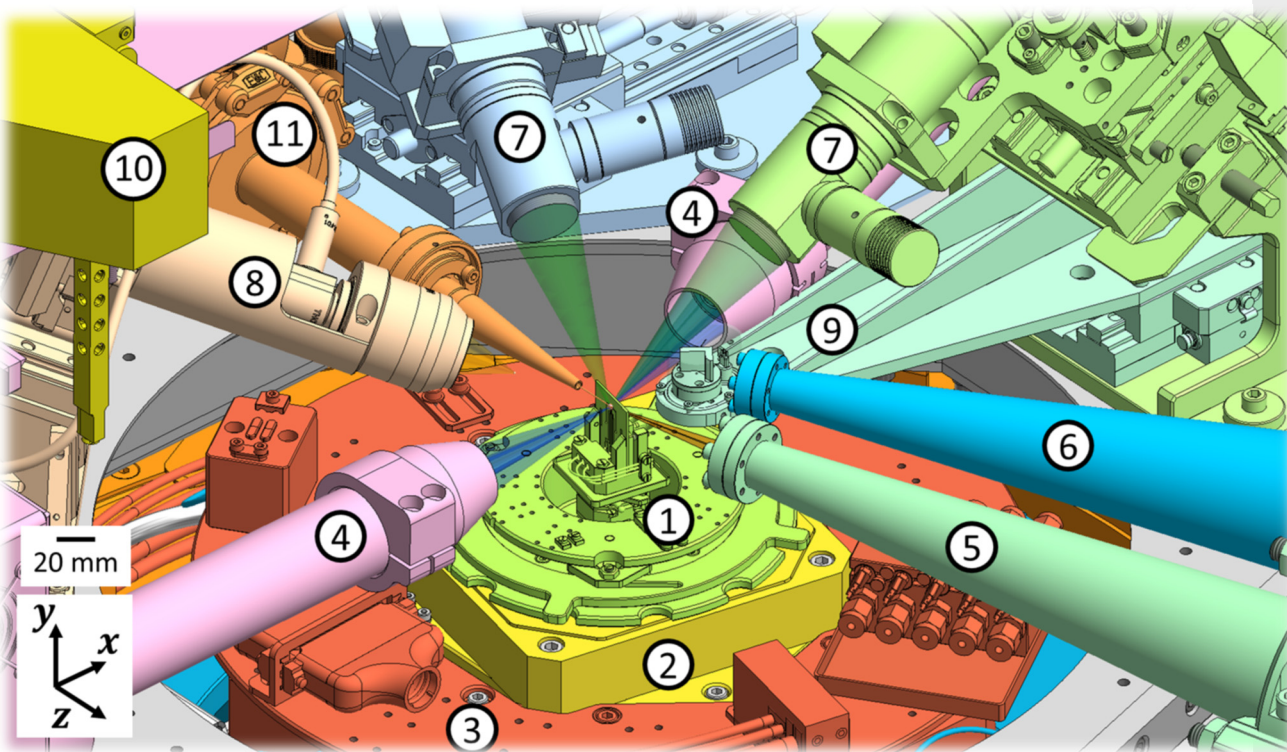
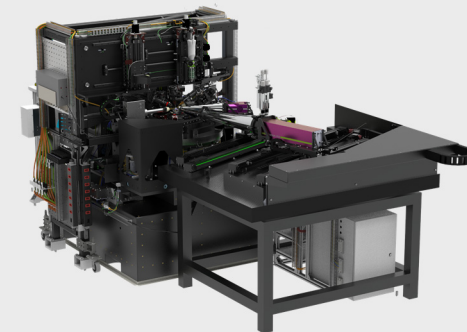
3.1. TARUMÃ

3.2. SAPOTI

3. The CARNAÚBA Beamline



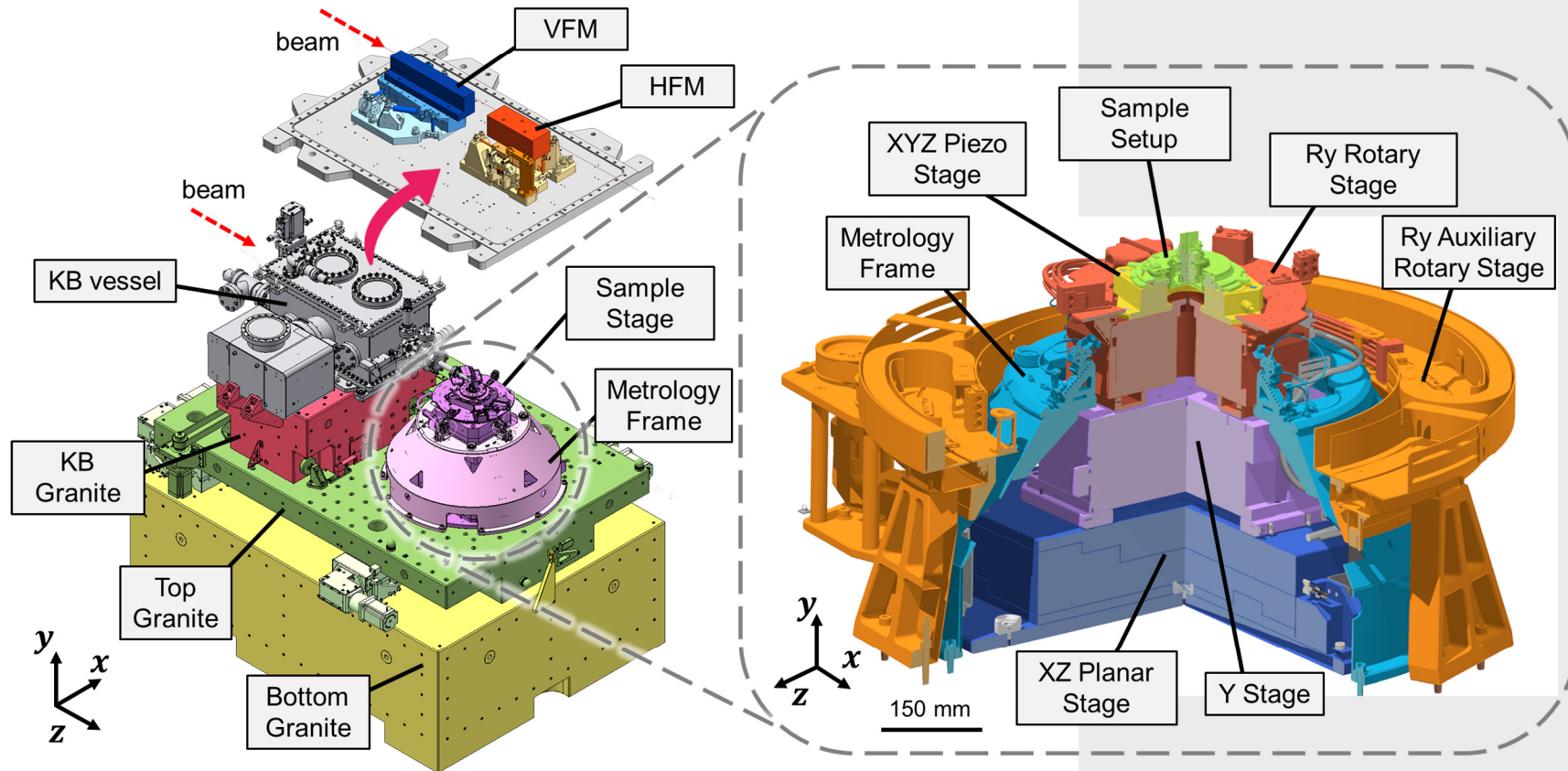
3.1. TARUMÃ: Overview



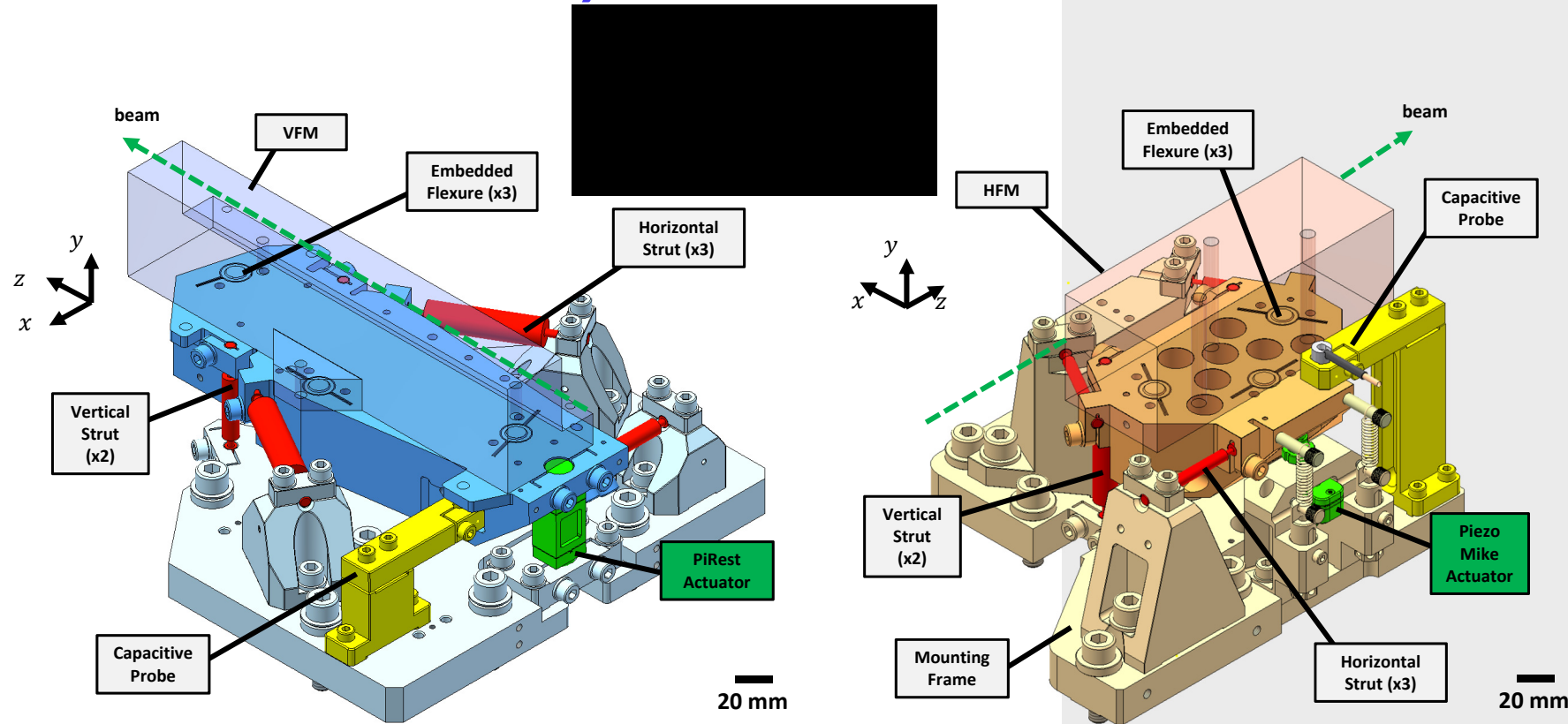
- | | | |
|----------------------------|--------------------------------|-----------------------------|
| 1. Sample setup; | 5. Transmission area detector; | 9. Crystal analyzer; |
| 2. XYZ piezo stage; | 6. Diffraction area detector; | 10. Pick-and place gripper; |
| 3. Rotary stage; | 7. Optical microscopes; | 11. KB vessel exit port. |
| 4. Fluorescence detectors; | 8. XEOL optics; | |

- Techniques:**
- XRD (Diffraction)
 - XAS (Absorption)
 - XRF (Fluorescence)
 - XEOL (Luminescence)
 - Ptycho-CDI
 - (Ptycho-)Bragg-CDI
 - Tomography

3.1. TARUMÃ: Overview



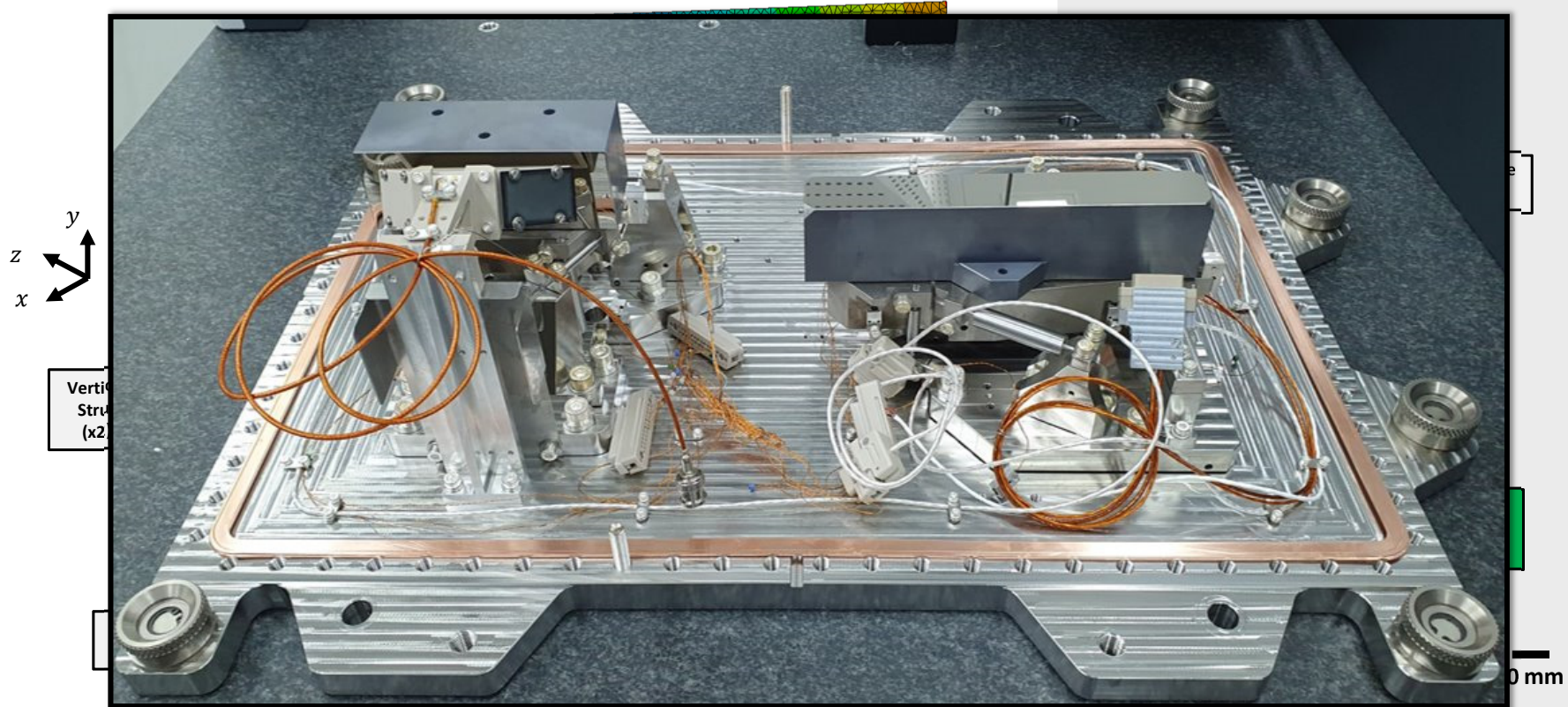
3.1. TARUMÃ: Exactly-constrained KB Mirrors



*Pitch modes > 1 kHz

(doi: 10.18429/JACoW-MEDSI2020-TUOB01)

3.1. TARUMÃ: Exactly-constrained KB Mirrors

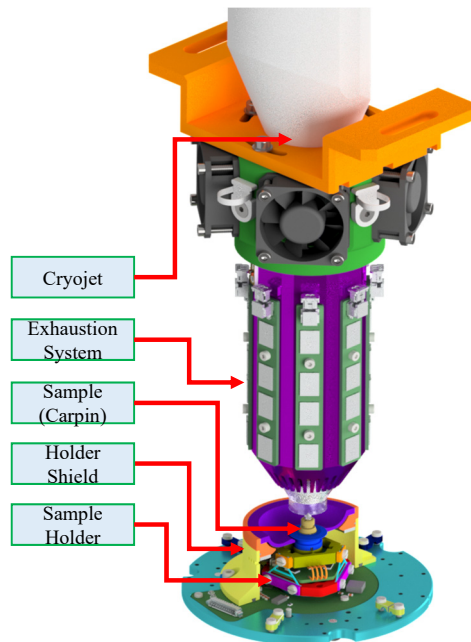


*Pitch modes > 1 kHz

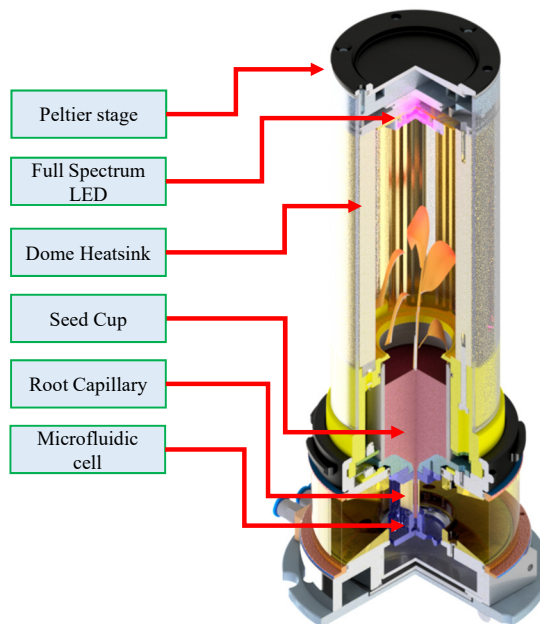
(doi: 10.18429/JACoW-MEDSI2020-TUOB01)

3.1. TARUMÃ: Sample Setups

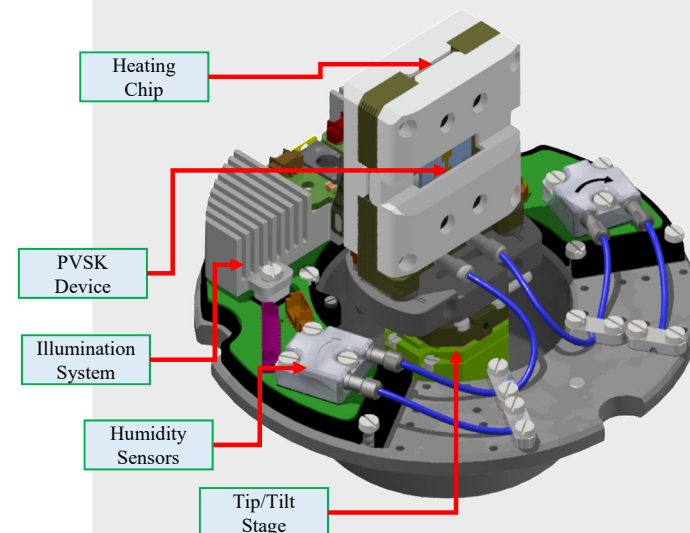
Cryogenic Setup



Rhizomicrocosm

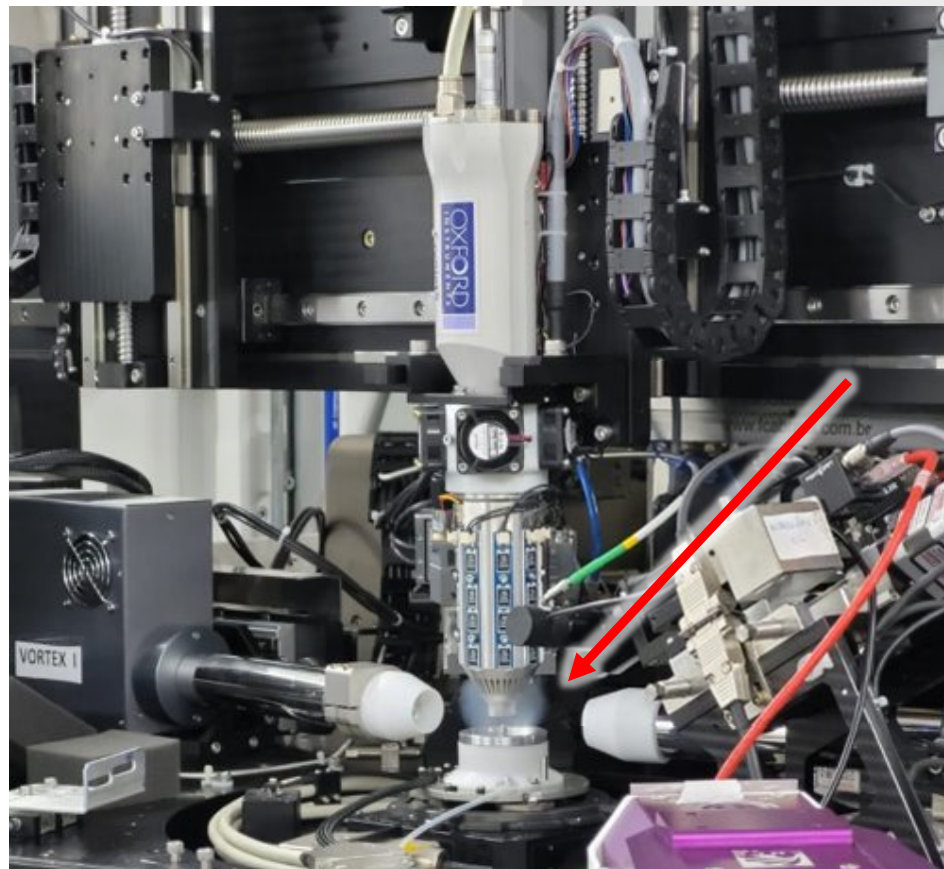
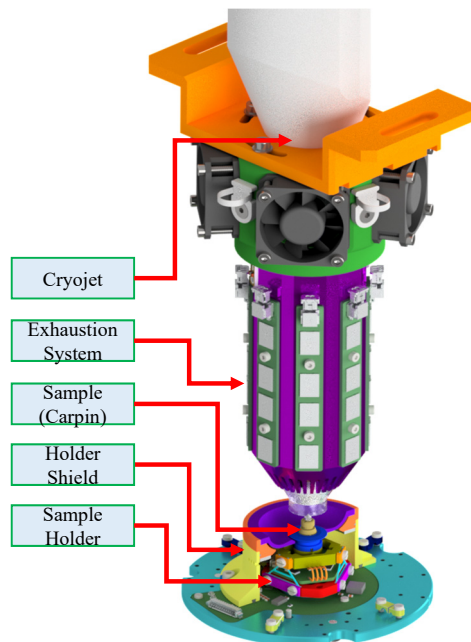


Perovskite Setup



3.1. TARUMÃ: Cryogenic Setup

Cryogenic Setup



(doi: 10.18429/JACoW-MEDSI2020-WEPC02)
(doi: 10.1088/1742-6596/2380/1/012108)

3.1. TARUMÃ: Image Resolution

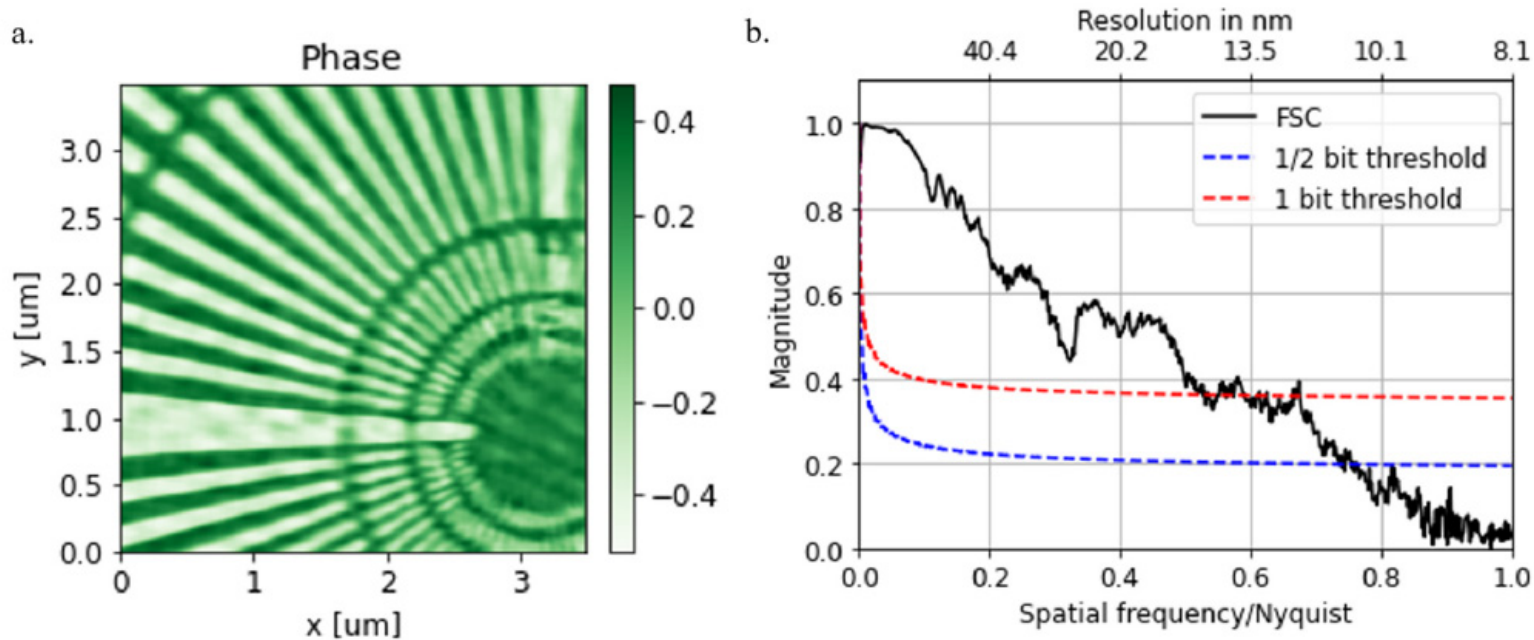
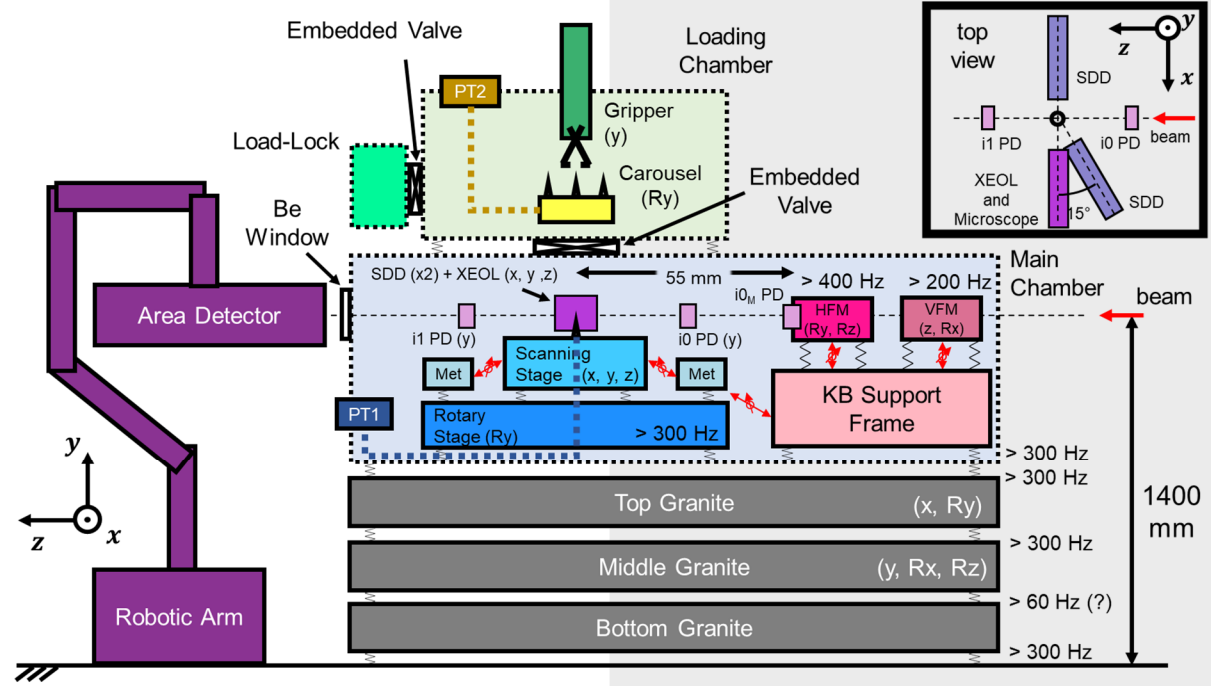
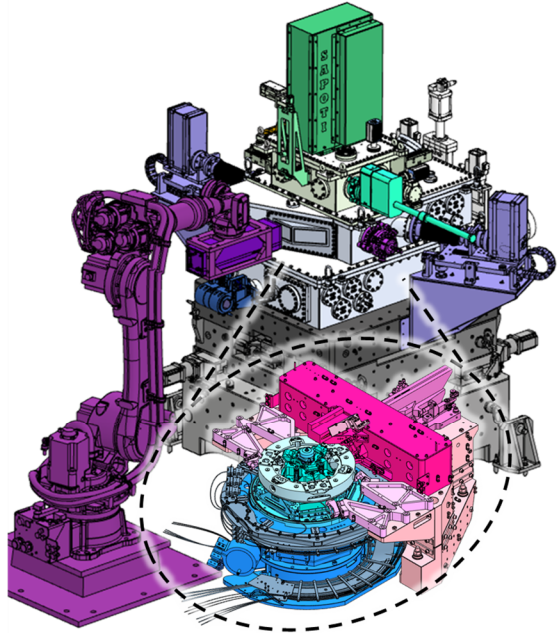
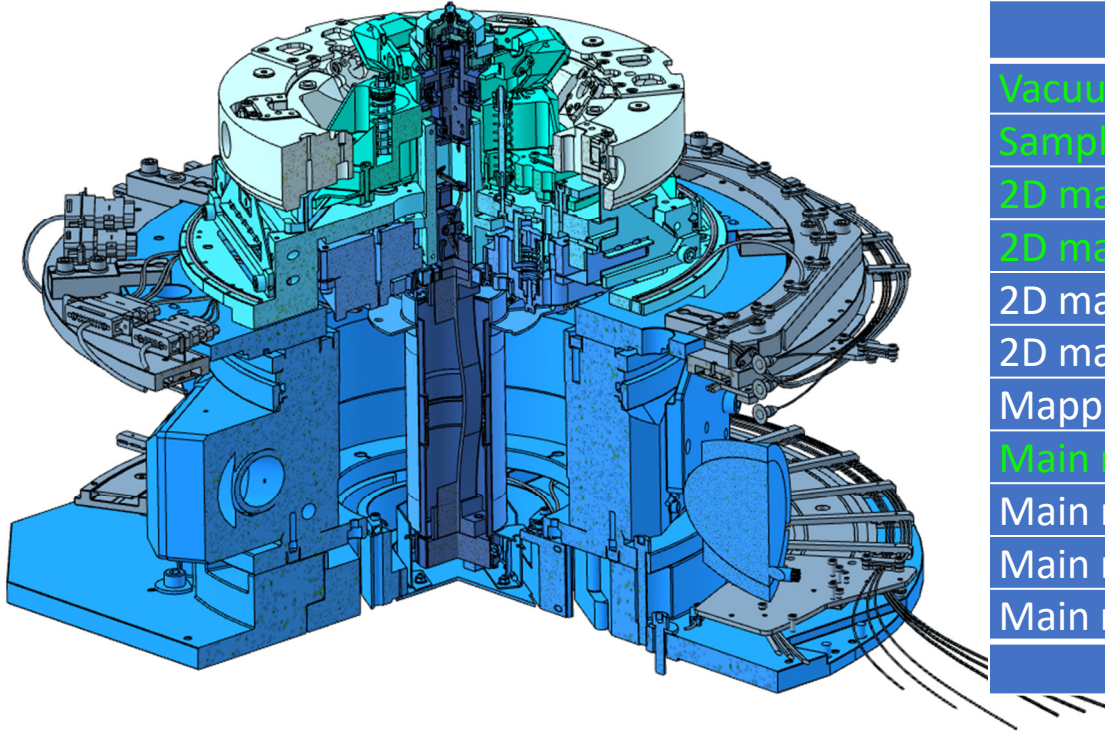


Fig. 20. Ptychography reconstruction of the Siemens star. (a) Zoom on the central portion of the image in Fig. 19a, showing the star's finest structures, (b) FSC analysis and comparison to the threshold criteria evaluated with PyNX [89].

3.2. SAPOTI: Overview



3.2. SAPOTI: Sample Stage Specifications

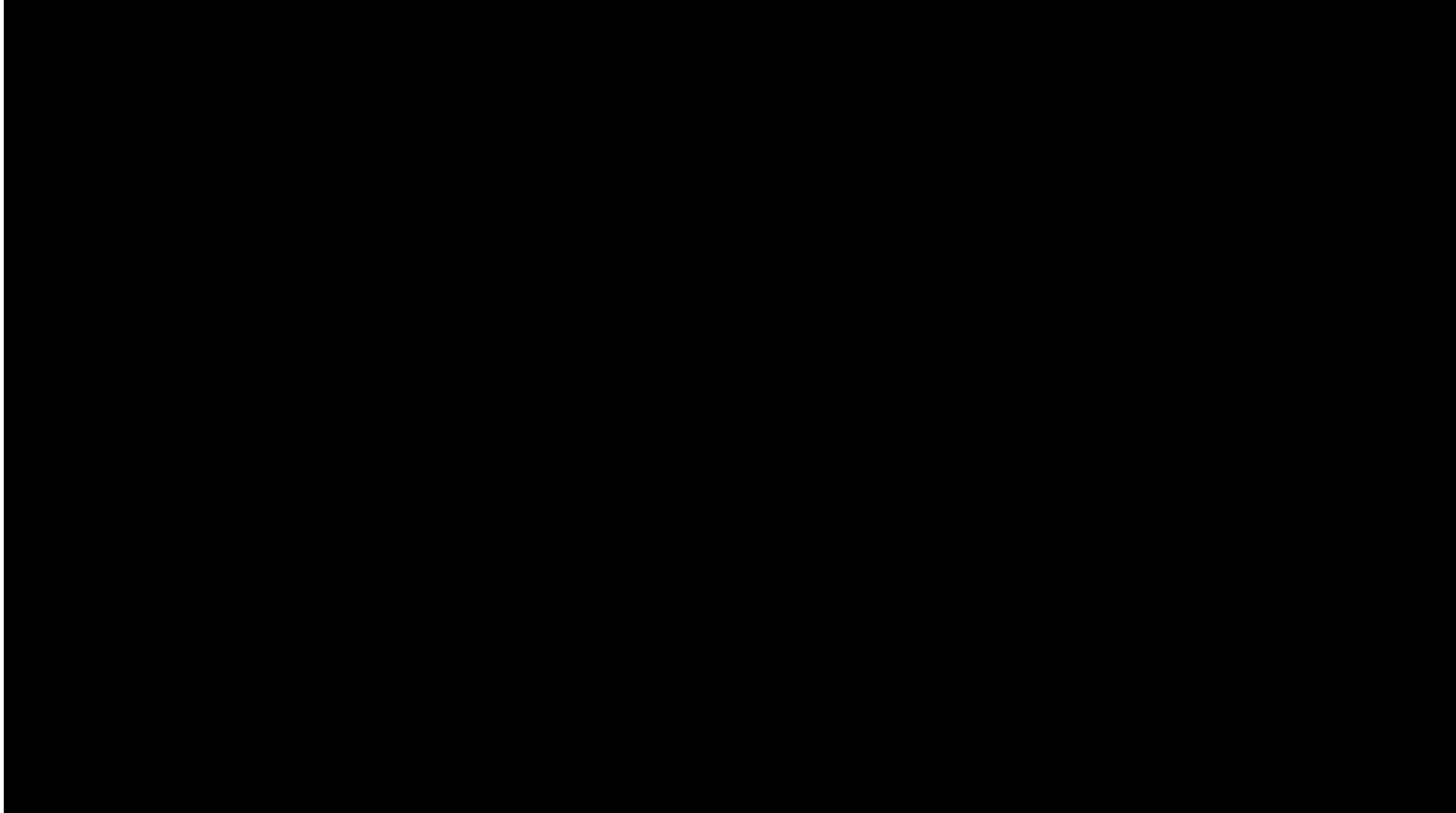


Parameter	Value
Vacuum level	$\sim 1e-9$ mbar
Sample Temperature	< 100 K
2D mapping range (XY)	± 1.5 mm
2D mapping stab. (XY)	1 nm RMS
2D mapping acc. (XY)	< 10 nm
2D mapping repeat. (XY)	5 nm
Mapping velocity	≤ 50 $\mu\text{m/s}$
Main rotation range (Ry)	220°
Main rotation stab. (Ry)	2 μrad
Main rotation acc. (Ry)	100 μrad
Main rotation repeat. (Ry)	10 μrad

3.2. SAPOTI: Sample Stage Motion (XYZ)

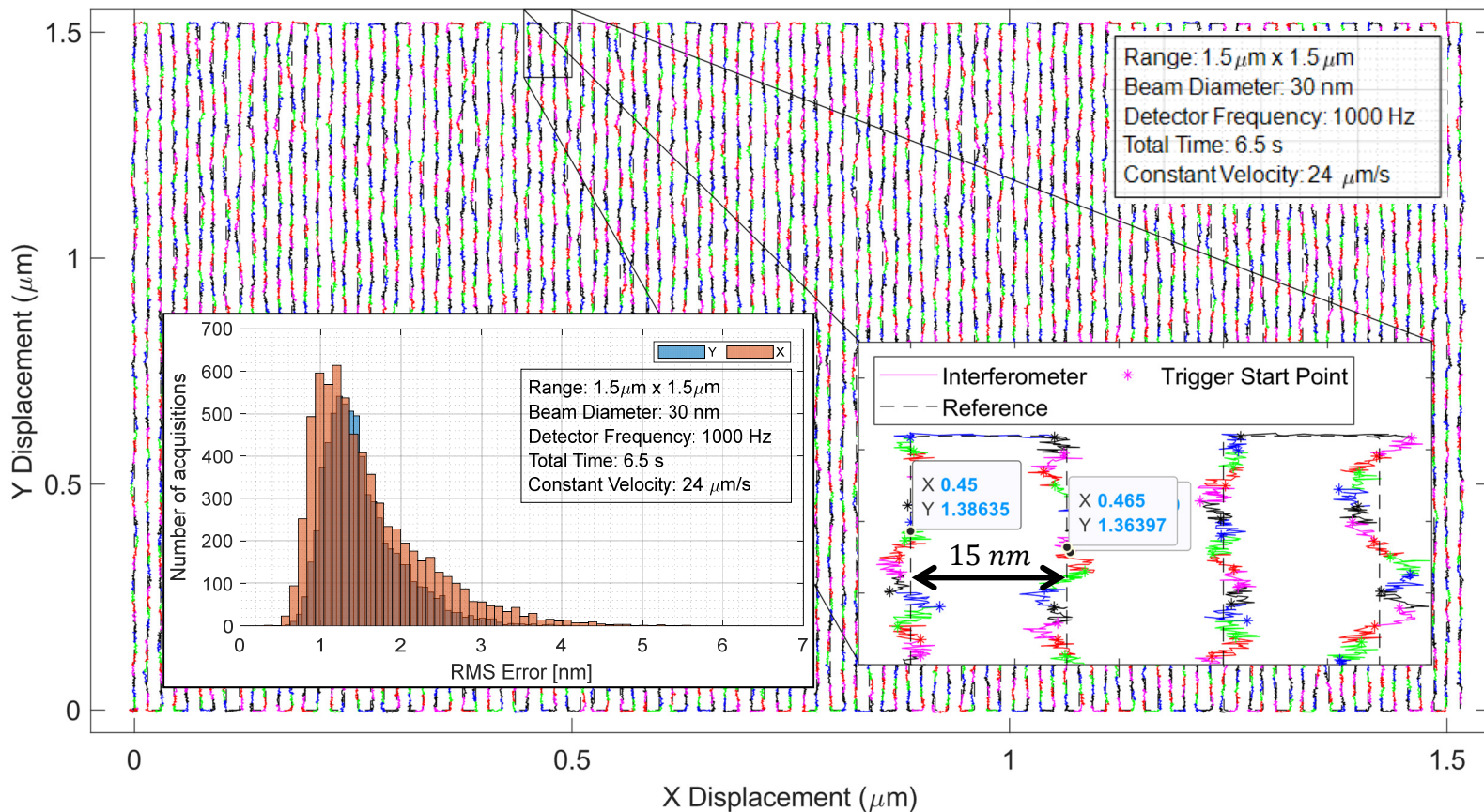


CNPq



8x speed

Trajectory Optimization (XY mapping)



Outline: Nanopositioning

- Introduction
- Motivation
- Commercial Scenario
- Development Framework
- Examples
- **Conclusions & Perspectives**

Conclusions

- Design principles and different technologies must be known for optimized solutions;
- Holistic and systemic design approaches should be considered for ultimate performances;
- Predictive design framework and modeling tools can improve design efficiency and assertiveness;
- New-generation beamlines tend to push toward industry-like high-end systems and throughput;
- People training and management may prove to be one of the critical bottlenecks in face of such complex systems.

Perspectives



- High-end mechatronics is still at an early stage within the beamline environment, but there is room for a quick evolution;
- Full beamline (IDs, slits, mirrors, monochromators, sample, detectors) coordination and calibration in motion and thermal aspects may be required for some ultimate high-performance experiments (e.g. spectroscopy);
- Model-based systems engineering (MBSE) shows great potential in handling ever more complex systems.

Thank you!

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